

RV COLLEGE OF ENGINEERING[®]

(Autonomous Institution Affiliated to VTU, Belagavi) R.V. Vidyaniketan Post, Mysore Road Bengaluru – 560 059



Scheme and Syllabus of I & II Semesters (Autonomous System of 2018 Scheme)

Master of Technology (M.Tech) in VLSI DESIGN & EMBEDDED SYSTEMS

DEPARTMENT OF ELECTRONICS & COMMUNICATION ENGINEERING **INNER FRONT COVER PAGE**

College Vision & Mission (To be included from our side)

RV COLLEGE OF ENGINEERING® (Autonomous Institution Affiliated to VTU, Belagavi) R.V. Vidyaniketan Post, Mysore Road Bengaluru – 560 059



Scheme and Syllabus of I & II Semesters (Autonomous System of 2018 Scheme)

Master of Technology (M.Tech) in VLSI DESIGN & EMBEDDED SYSTEMS

DEPARTMENT OF ELECTRONICS & COMMUNICATION ENGINEERING

Department Vision & Mission

VISION

Imparting quality technical education through interdisciplinary research, innovation and teamwork for developing inclusive & sustainable technology in the area of Electronics and Communication Engineering

MISSION

- To impart quality technical education to produce industry-ready engineers with a research outlook.
- To train the Electronics & Communication Engineering graduates to meet future global challenges by inculcating a quest for modern technologies in the emerging areas.
- To create centers of excellence in the field of Electronics & Communication Engineering with industrial and university collaborations.
- To develop entrepreneurial skills among the graduates to create new employment opportunities

ABBREVIATIONS

Sl. No.	Abbreviation	Meaning
1.	VTU	Visvesvaraya Technological University
2.	BS	Basic Sciences
3.	CIE	Continuous Internal Evaluation
4.	SEE	Semester End Examination
5.	CE	Professional Core Elective
6.	GE	Global Elective
7.	HSS	Humanities and Social Sciences
8.	CV	Civil Engineering
9.	ME	Mechanical Engineering
10.	EE	Electrical & Electronics Engineering
11.	EC	Electronics & Communication Engineering
12.	IM	Industrial Engineering & Management
13.	EI	Electronics & Instrumentation Engineering
14.	СН	Chemical Engineering
15.	CS	Computer Science & Engineering
16.	TE	Telecommunication Engineering
17.	IS	Information Science & Engineering
18.	BT	Biotechnology
19.	AS	Aerospace Engineering
20.	PHY	Physics
21.	CHY	Chemistry
22.	MAT	Mathematics

I	N)F	EX	

	I Semester					
Sl. No.	Course Code	Course Title	Page No.			
1.	18MVE11	Digital System Design using Verilog	9			
2.	18MVE12	Advanced Embedded System Design	11			
3.	18MVE13	Digital IC Design	14			
4.	18HSS14	Professional Skill Development	16			
5.	18MVE1AX	Elective – A	18 - 23			
6.	18MVE1BX	Elective – B	24 - 29			
		GROUP A: CORE ELECTIVES				
1.	18MVE1A1	Advanced Computer Architecture	18			
2.	18MVE1A2	ASIC Design	20			
3.	18MVE1A3	Algorithms for VLSI Design	22			
		GROUP B: CORE ELECTIVES				
1.	18MVE1B1	MEMS and Smart Systems	24			
2.	18MVE1B2	System On Chip Design	26			
3.	18MVE1B3	Advanced VLSI Devices	28			

	II Semester					
Sl. No.	Course Code	Course Title	Page No.			
1.	18MVE21	Analog IC Design	30			
2.	18MVE22	System Verilog for Design & Verification	32			
3.	18IM23	Research Methodology	34			
4.	18MVE24	Minor Project	36			
5.	18MVE2CX	Elective – C	37 - 42			
6.	18MVE2DX	Elective – D	43 - 47			
7.	18XX2GX	Global Elective	49 - 68			
		GROUP C: CORE ELECTIVES				
1.	18MVE2C1	VLSI Testing	37			
2.	18MCS2C2	Machine Learning	39			
3.	18MVE2C3	High speed VLSI Design	41			
GROUP D: CORE ELECTIVES						
1.	18MVE2D1	Low Power VLSI Design	43			
2.	18MVE2D2	Advanced Embedded Processors	45			
3.	18MVE2D3	VLSI Digital Signal Processing Systems	47			
		GROUP G: GLOBAL ELECTIVES				
1.	18CS2G01	Business Analytics	49			
2.	18CV2G02	Industrial & Occupational Health and Safety	51			
3.	18IM2G03	Modeling using Linear Programming	53			
4.	18IM2G04	Project Management	55			
5.	18CH2G05	Energy Management	57			
6.	18ME2G06	Industry 4.0	59			
7.	18ME2G07	Advanced Materials	61			
8.	18CHY2G08	Composite Materials Science and Engineering	63			
9.	18PHY2G09	Physics of Materials	65			
10.	18MAT2G10	Advanced Statistical Methods	67			

R V COLLEGE OF ENGINEERNG, BENGALURU-560 059 (Autonomous Institution Affiliated to VTU, Belagavi) DEPARTMENT OF ELECTRONICS & COMMUNICATION ENGINEERING M.Tech in VLSI DESIGN & EMBEDDED SYSTEMS

		FIRST SEMES	TER CRED	IT SCHEM	E			
SI.					Credit Allocation			
No.	Course Code	Course Title	BoS	L	Т	Р	Total Credits	
1	18MVE11	Digital System Design using Verilog	EC	4	0	0	4	
2	18MVE12	Advanced Embedded System Design	EC	3	1	1	5	
3	18MVE13	Digital IC Design	EC	3	1	1	5	
4	18HSS14	Professional Skill Development	HSS	0	0	0	0	
5	18MVE1AX	Elective – A	EC	4	0	0	4	
6	18MVE1BX	Elective – B	EC	4	0	0	4	
	Total number of Credits				2	2	22	
	Total Nu	mber of Hours / Week		18	4	6	28	

	SECOND SEMESTER CREDIT SCHEME						
SI.	Course			Credit Allocation			
No.	Code	Course Title	BoS	L	Т	Р	Total Credits
1	18MVE21	Analog IC Design	EC	3	1	1	5
2	18MVE22	System Verilog for Design & Verification	EC	3	1	0	4
3	18IM23	Research Methodology	IM	3	0	0	3
4	18MVE24	Minor Project	EC	0	0	2	2
5	18MVE2C X	Elective – C	EC	4	0	0	4
6	18MVE2D X	Elective – D	EC	4	0	0	4
7	18XX2GX	Global Elective	Respective boards	3	0	0	3
	Total number of Credits			20	2	3	25
	Total Number of Hours / Week				4	9	33

		I Semester			
		GROUP A: CORE ELECTIVES			
Sl. No.	Course Code	Course Title			
1.	18MVE1A1	Advanced Computer Architecture			
2.	18MVE1A2	ASIC Design			
3.	18MVE1A3	Algorithms for VLSI Design			
		GROUP B: CORE ELECTIVES			
1.	18MVE1B1	MEMS and Smart Systems			
2.	18MVE1B2	System On Chip Design			
3.	18MVE1B3	Advanced VLSI Devices			
		II Semester			
		GROUP C: CORE ELECTIVES			
1.	18MVE2C1	VLSI Testing			
2.	18MCS2C2	Machine Learning			
3.	18MVE2C3	High speed VLSI Design			
	GROUP D: CORE ELECTIVES				
1.	18MVE2D1	Low Power VLSI Design			
2.	18MVE2D2	Advanced Embedded Processors			
3.	18MVE2D3	VLSI Digital Signal Processing Systems			

	GROUP E: GLOBAL ELECTIVES					
Sl. No.	Host Dept	Course Code	Course Title	Credits		
1.	CS	18CS2G01	Business Analytics	3		
2.	CV	18CV2G02	Industrial & Occupational Health and Safety	3		
3.	IM	18IM2G03	Modelling using Linear Programming	3		
4.	IM	18IM2G04	Project Management	3		
5.	СН	18CH2G05	Energy Management	3		
6.	ME	18ME2G06	Industry 4.0	3		
7.	ME	18ME2G07	Advanced Materials	3		
8.	CHY	18CHY2G08	Composite Materials Science and Engineering	3		
9.	PHY	18PHY2G09	Physics of Materials	3		
10.	MAT	18MAT2G10	Advanced Statistical Methods	3		

		Semester I				
		DIGITAL SYSTEM DESIGN USIN	G VERILOG			
Course Code	:	18MVE11	CIE Marks	:	100	
Credits : L:T:P	:	4:0:0	SEE Marks	: 100		
Hrs	:	48L	SEE Duration	:	3 Hrs	
		Unit – I	·		10 Hrs	
Introduction to Verification of HDI Verification of HDI Verilog Data Types Reduction, Relation Verilog Primitives and Signal Resolu Simulation, Sized M Introduction to De Digital Systems a Architecture, Funce	 Introduction to Verilog and Design Methodology: Introduction to Verilog: Verilog IEEE standards, Application Areas and Abstraction levels, Need of verification of HDL design, Simulation and Synthesis, Test-benches, Verilog Data Types: Net, Register and Constant. Verilog Operators: Logical, Arithmetic, Bitwise, Reduction, Relational, Concatenation and Conditional, Number representation and Verilog ports. Verilog Primitives. Logic Simulation, Design Verification, and Test Methodology: Four-Value Logic and Signal Resolution in Verilog, Test Methodology Signal Generators for Test benches, Event-Driven Simulation, Sized Numbers. Propagation Delay. Introduction to Design Methodology: Digital Systems and Embedded Systems, Real-world circuits. Design Methodology: Design Flow-Arabitactura, Eunctional design, and verification, Sunthasis, Physical design, Optimization, Arabitactura, Eunctional design, and verification, Sunthasis, Physical design, Optimization, Arabitactura, Eunctional design, and verification, Sunthasis, Physical design, Design, Arabitactura, Eunctional design, and verification, Sunthasis, Physical design, Design, Arabitactura, Eunctional design, and verification, Sunthasis, Physical design, Design, Arabitactura, Eunctional design, and verification, Sunthasis, Physical design, Design, Arabitactura, Eunctional design, Physical design					
Timing and Power,	Sys	tem representation.			40.77	
		Unit – 11			10 Hrs	
Number Basics: Unsigned and Signed Integers, Fixed-point and Floating-point Numbers. BooleanFunctions and Boolean Algebra, Verilog models for Boolean switching function, Binary Coding.Behavioural Modelling: Latches and Level-Sensitive Circuits in Verilog, Cyclic Behavioural Models ofFlip-Flops and Latches, Cyclic Behaviour and Edge Detection. A Comparison of Styles for Behaviouralmodelling, Behavioural Models of Multiplexers, Encoders, Decoders and Arithmetic circuits.Dataflow Modelling: Boolean Equation-Based Models of Combinational Logic, Propagation Delay andContinuous Assignments. Dataflow Models of a Linear-Feedback Shift Register. Modelling DigitalMachines with Repetitive Algorithms Machines with Multicycle Operations. Tasks & Functions.Structural Modelling: Design of Combinational Logic, Verilog Structural Models, Module Ports, Top-Down Design and Nested Modules. Gate level modelling.Unit – III10 Hrs						
Synthesis of Digital Sub-systems: Synthesis of Combinational Sub-systems: Introduction to Synthesis, Synthesis of Combinational Logic, Synthesis of Sequential Logic with Latches, Synthesis of Three-state Devices and Bus Interfaces. Synthesis of Sequential Sub-systems: Synthesis of Sequential Logic, State Machines, Registered Logic, State Encoding, Synthesis of Implicit State Machines, Registered Logic, Unit – IV						
System Implemen	tati	on Fabrics and Accelerators: Introduction	on of Programmable I	Logi	c Array (PLA),	
Programmable Array Logic (PAL), Programmability of PLDs. Complex PLDs (CPLDs), Field- Programmable Gate Arrays (Artix-7 and Virtex-5) The Role of FPGAs in the ASIC Market, FPGA Technologies. Verilog-Based Design Flows for FPGAs and ASICs. Comparison of design implementation using CPLDs, FPGA and ASIC. System Accelerators: Concepts, Case study: Video Edge detection, Verification of accelerators. User-Defined Primitives: Combinational Primitives: Basic Features of User-Defined Primitives, Describing Combinational Logic Circuits. Sequential Primitives: Level-Sensitive Primitives, Edge- Sensitive Primitives.						
		Unit – V			9 Hrs	
Processor Design a Design of Process (overview). Design	and sor n: H	System Development : Architectures: Functional Units for A lierarchical Decomposition STG-Based	Addition, Subtraction Controller Design, E	and fficie	Multiplication ent STG-Based	

Sequential Binary Multiplier.

Interfacing Concepts: Embedded Computer Organization, Instruction and Data, Memory Interfacing. I/O Interfacing: I/O devices, I/O controllers, Parallel Buses, Serial Transmission.

Course Outcomes:

After taking up this course, the student will be able to:

CO1: Understand the digital system designs skills using VERILOG HDL based on IEEE-1364 standards and managed by Open Verilog International (OVI).

CO2: Demonstrate the skill on cost-effective system designs through proper selection of implementation fabrics for the desired application.

CO3: Analyze complete systems and build small scale applications using Interfacing concepts.

CO4: Design and implement complete digital systems using VERILOG HDL and demonstrate the innovation skills.

Reference Books:

- 1. Michael D. Ciletti, "Advanced Digital Design With the Verilog HDL," 2E, PHI, ISBN: 978–0–07– 338054–4 2015.
- 2. Peter J. Ashenden, "Digital Design: An Embedded Systems Approach Using VERILOG", Elsevier, ISBN: 978-0-12-369527-7, 2010.
- 3. Charles Roth, Lizy K. John, Byeong Kil Lee, "Digital Systems Design Using Verilog," Cengage Learning, *ISBN*-10: 1285051076, 2015.
- 4. Stephen Brown and Zvonko Vranesic, "Fundamentals of Digital Logic with Verilog Design," 6E, McGraw Hill publication, ISBN: 978–0–07–338054–4, 2014.
- 5. J. Bhasker, "Verilog HDL Synthesis A Practical Primer," Star Galaxy Publishing, ISBN: 0-9650391-5-3, 1998.

Continuous Internal Evaluation (CIE): Total marks: 100

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

			Semester I			
	ADVANCED EMBEDDED SYSTEM DESIGN					
Course Code	:	18MVE12		CIE Marks	:	100 + 50
Credits : L:T:P	:	3:1:1		SEE Marks	:	100 + 50
Hrs	:	48L +36 P		SEE Duration	:	3 Hrs +3 Hrs
		Uı	nit — I			10 Hrs
Introduction to Embedded System Design Introduction, Characteristics of Embedding Computing Applications, Concept of Real time Systems, Challenges in Embedded System Design, Design Process: Requirements, Specifications, Hardware Software Partitioning, Architecture Design, Designing of Components, System Integration Embedded System Architecture Instruction Set Architectures with examples, Memory system Architecture: Von Neumann, Harvard, caches, Virtual Memory, Memory Management, I/O sub system: Busy wait I/O,DMA, Interrupt Driven						
Execution, Multi	Co	re CPUs, CPU Power	Consumption, I	Benchmarking Stand	lard	s: MIPS, MFLOPS,
MMACS, Coreman	k	T T	.:4 17			1A TT.
			111 – 11			10 Hrs
Designing Embedded System Hardware –I CPU Bus: Bus Protocols, Bus Organisation, Memory Devices and their Characteristics: RAM, EEPROM, Flash Memory, DRAM; I/O Devices: Timers and Counters, Watchdog Timers, Interrupt, Controllers, DMA Controllers, A/D and D/A Converters, Displays, Keyboards, Infrared devices						
Designing Embedd	led	System Hardware –II				_ • •
Component Interfa Programmed IO, Designing with Pro	icin Me	g: Memory interfacing mory Mapped IO, Intersors: System Architectur	with case stud rfacing Protoco e, FPGA based	y; I/O Device Intert ols: SPI, I2C, CAN Design, Processor Se	faci I, U elec	ng with case Study: JSB, Reset Circuits, tion Criteria
Designing Embedd	dod	Un System Software I	$\mathbf{I}\mathbf{U} - \mathbf{I}\mathbf{V}$			9 Hrs
Designing Embedded System Software –I Application Software, System Software, Use of High Level Languages: C,C++,Java, Programming & Integrated Development Environment tools: Editor, Compiler, Linker, Automatic Code Generators, Debugger, Board Support Library, Chip Support Library, Analysis and Optimization: Execution Time, Energy & Power, Program Size; Program Validation & Verification, Embedded System Coding Standards: MISRA C 2012/CERT, Standards in Automobiles, Aerospace & Biomedical Applications.						
Destantes Freehad	.		$\mathbf{n}\mathbf{t} = \mathbf{v}$			9 1115
Designing Embedded System Software –II OS based Design, Real Time Kernel, Process& Thread, Inter Process Communications, Synchronization, Case Study: RTX-ARM, Evaluating and Optimising Operating System Performance: Response time Calculation, Interrupt Latency, Time Loading, Memory Loading, Case Study: Embedded Control Applications-Software Coding of a PID Controller, PID Tuning, IoT based Resource Monitoring						
		LAI	B COMPONEN	ЛТ		
Experiments on ba 1. Write application evaluation board ar 2. Write Systick_ha driven IO. 3.Write driver for sensor interface. We value output. Development 4. Write I2C driver	are on and c and AI Vrit lop	metal programming program to interface LH lemonstrate polling-based dler to accurately contro DC0 in LPC 1857 MCU e driver functions for A main function using API t LPC1857. Develop follo	EDs and push d d IO operation. d the delay bet J. Display digit DC initialization (s of ADC drive powing APIs to s	buttons to GPIOs o ween toggling of LF al value on GLCD on, ADC start of con r to test the functiona upport I2C.	f L EDs and nver ality	PC 1857 cortex M3 to support interrupt demonstrate analog rsion, reading digital

uint32_t I2C_Init (void); uint32_t I2C_Start (void); uint32_t I2C_Stop (void); uint32_t I2C_Addr (uint8_t adr, uint8_t dir); uint32_t I2C_Write (uint8_t byte); uint32_t I2C_Read (uint32_t ack, uint8_t *byte);

5. Write driver to support LM75a digital temperature sensor through I2C. Make use of APIs developed in experiment 4 to interface LM75a to LPC 1857 MCU. Test the functionality by displaying temperature values on GLCD.

6. Write application program to realize FIR filter on STM32F4 cortex M4 development board. Test the filtering operation on signal generated from function generator and interfaced to STM32F4 development board through WolfsonPI codec.

Experiments using RTOS

1. Create a multitasking application program to demonstrate creation of tasks. Task1 is expected to control the blinking two LEDs and Task2 is to change font and colour of the textual display on GLCD concurrently. Use APIs of RL-RTX/Freertos real time kernel. Configure systick timer to generate tick interval.

2. Create multitasking program to demonstrate task synchronization. Task1 is expected to display LED blinking pattern and Task2 display textual message on GLCD. Synchronize the access of GLD using mutex/semaphore using APIs of RL-RTX/Freertos.

3. Create a multitasking program to demonstrate event flags to synchronize task execution. Create four tasks to simulate the operation of stepper motor driver. Use four LEDs blinking to simulate the activation of the four output driver stages. Create another concurrently executing task to display text on GLCD. The stepper motor driver tasks are expected to run sequentially.

4. Create multitasking program to demonstrate IPC using mailbox. Create a task to read a digital value from ADC and send to another task executing concurrently through mailbox. Synchronize the execution of tasks. Use APIs of RL-ARM/Freertos real time kernel.

5. Create a 'Blinky' project using RL-ARM real time Kernel to simulate the operations of step-motor driver. Use four LEDs blinking to simulate the activation of the four output driver stages. Create other two tasks executing concurrently and competing for GLCD. The first task displays status of LEDs blinking on GLCD and second task displays a string with changing colour of font and background. Use suitable mechanism to protect shared resource.

Expected Course Outcomes:

After going through this course the student will be able to:

CO1: Describe hardware & software of an embedded systems for real time applications with suitable processor architecture, memory and communication interface.

CO2: Design embedded software & hardware to meet given constraints with the help of modern engineering tools.

CO3: Demonstrate compliance of prescribed safety norms through implementation of the identified engineering problems pertaining to automobiles, aerospace & biomedical applications.

CO4: Engage in self study to design, implement and demonstrate open ended problem

Reference Books:

1.	James K Peckol, "Embedded Systems – A contemporary Design Tool", John Weily, 2008, ISBN: 0-444-51616-6
2.	Shibu K V, "Introduction to Embedded Systems", Tata McGraw Hill Education Private Limited, 2009, ISBN: 10: 0070678790
3.	David E.Simon, "Embedded Software Primer", Addison Wesley, ISBN-13: 978-0201615692
4.	Barry B.Brey, "The Intel Micro-processors, Architecture, Programming and Interfacing", 6th Edition,

	Pearson Education.
5.	Steve Heath, "Embedded System Design", Elsevier, 2nd Edition, 2004.
6.	Reference Manuals: RTX-ARM, MISRA C 2012, CERT, IS26262, DO-178B, IEC 62304

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Scheme of Continuous Internal Evaluation (CIE) for Practicals: (50 Marks)

The Laboratory session is held every week as per the time table and the performance of the student is evaluated in every session. The average of marks over number of weeks is considered for 30 marks. At the end of the semester a test is conducted for 10 marks. The students are encouraged to implement additional innovative experiments in the lab and are rewarded for 10 marks. Total marks for the laboratory is 50.

Semester End Evaluation (SEE): Total marks: 100+50=150 Theory (100 Marks) + Practical (50 Marks) = Total Marks (150)

Scheme of Semester End Examination (SEE) for 100 marks:

The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

Scheme of Semester End Examination (SEE); Practical (50 Marks)

SEE for the practical courses will be based on experiment conduction with proper results, is evaluated for 40 marks and Viva is for 10 marks. Total SEE for laboratory is 50 marks.

Semester I								
DIGITAL IC DESIGN (Theory and Practice)								
Course Code	:	18MVE13		CIE Marks	:	100+50		
Credits : L:T:P	:	3:1:1		SEE Marks	:	100+50		
Hrs	:	48L+36P		SEE Duration	:	3 Hrs + 3	Hrs	
		Uı	nit — I				10 Hrs	
Introduction: Issu Digital Design MOS Transistor: scaling Implementation s circuit design, cell	es in Dev trate base	n Digital IC Design, Des vice structure, MOSFET egies for Digital ICs: I ad design methodology.	sign abstraction '- static & dyna Digital circuit ir semicustom des	levels in digital circ amic behavior, seco applementation appro-	cuits ondar oach	, Quality Me y effects, te es- overviev	trics of a chnology v Custom	
		Un	nit – II	8			10 Hrs	
CMOS inverter: S CMOS Combinat Logic, Pass Transi Power Dissipation	Station iona stor of D	c CMOS Inverter: static al Logic Circuit Design Logic. Dynamic CMOS Dynamic logic, Signal int	and dynamic B n: Static CMO Design: Dyna tegrity issues, C	ehavior, Componen S Design: Compler mic Logic Design C ascading Dynamic	ts of nent Consi gates	Energy and ary CMOS derations. S	Power , Ratioed peed and	
		Un	1t – 111				10 Hrs	
Memory & Array Interconnects: Re Timing Issues: T Skew/Jitter and Im	stru sisti 'imii pact	Un ve, Capacitive and Induc on Performance, Clock	y core – ROM, it – IV ctive Parasitics (gital systems – Distribution tec	SRAM, DRAM, Set (basics) - Synchronous Det chniques, Latch base	sign	- Origins	AM 9 Hrs of Clock	
		Ur	nit – V	1,		6	9 Hrs	
Arithmetic buildin static adder, mirror carry lookahead ad Manufacturing C process flow.	Onit – v9 HrsArithmetic building blocks design: Data paths in digital processor architectures – Adder, binary adder, static adder, mirror adder, TG based adder, carry bypass adder, linear and square root carry select adder, carry lookahead adder, Multiplier- array, carry save multiplierManufacturing CMOS Integrated Circuits: Silicon wafer, Photolithography, Process steps, CMOS process flow.							
			omponent				30 Hrs	
 Introduction to Cadence environment; setup Linux environment; create schematic and symbol, introduction to netlist, technology library. Inverter static characteristics Inverter dynamic characteristics Design and Analysis of NAND, NOR and complex gates Layout, DRC, LVS, RCX and post-layout simulation of CMOS Inverter Layout of CMOS NAND, NOR Inverter static characteristics LEF file generation LIB file generation Synthesis of combinational logics Case study: Synthesis of serial adder and PAR using Encounter tool. 								

Expected Course Outcomes:

After taking up this course, the graduate will be able to:

- CO1: Investigate device, circuit & system aspects of digital IC design
- CO2: Analyze the functionality of digital integrated circuits & systems
- CO3: Design and implement digital integrated circuit & systems

CO4: Evaluate the different performance parameters of a digital integrated circuits & systems

Reference Books:

1.	Jan M.Rabaey, Anantha Chadrakasan, Borivoje Nikolic, "Digital Integrated Circuits: A Design
	Perspective", (2/e), Pearson 2016, ISBN-13: 978-0130909961
0	E il D I I III I III I I I I I I I I I I I

- 2. Erik Brunvand, "Digital VLSI Chip Design with Cadence and Synopsys CAD Tools", Pearson 2009, ISBN-13: 9780321547743
- 3. David A Hodges, Horace G Jackson and Resve A Saleh, "Analysis and Design of Digital Integrated Circuits in Deep Submicron Technology" TMH.2005, ISBN-13: 978-0072283655
- 4. Sung MO Kang, Yousuf Leblebici, "CMOS Digital Integrated Circuits"; Tata McGrawHill, (3/e), ISBN: 0-7923-7246-8
- 5. Neil H.E. Weste, David Harris, Ayan Banerjee, "CMOS VLSI Design", Pearson Education, (3/e), 2006,ISBN: 0321149017
- Continuous Internal Evaluation (CIE): Total marks: 100+50=150

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Scheme of Continuous Internal Evaluation (CIE) for Practicals: (50 Marks)

The Laboratory session is held every week as per the time table and the performance of the student is evaluated in every session. The average of marks over number of weeks is considered for 30 marks. At the end of the semester a test is conducted for 10 marks. The students are encouraged to implement additional innovative experiments in the lab and are rewarded for 10 marks. Total marks for the laboratory is 50.

Semester End Evaluation (SEE): Total marks: 100+50=150

Theory (100 Marks) + Practical (50 Marks) = Total Marks (150)

Scheme of Semester End Examination (SEE) for 100 marks:

The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

Scheme of Semester End Examination (SEE); Practical (50 Marks)

SEE for the practical courses will be based on experiment conduction with proper results, is evaluated for 40 marks and Viva is for 10 marks. Total SEE for laboratory is 50 marks.

Semester I							
Professional Skill Development							
Course Code: 18HSS14	CIE Marks: 50						
Credits: L: T:P 3:0:0	SEE Marks: Audit Course						
Hours: 18L							

Unit – I	03 Hrs						
Communication Skills: Basics of Communication, Personal Skills & Presentation	Skills –						
Introduction, Application, Simulation, Attitudinal Development, Self Confidence, SWOC analysis.							
Resume Writing: Understanding the basic essentials for a resume, Resume writing tips Gui	delines for						
better presentation of facts. Theory and Applications.							
Unit - II	08 Hrs						
Quantitative Aptitude and Data Analysis: Number Systems, Math Vocabulary, fraction	decimals,						
digit places etc. Simple equations - Linear equations, Elimination Method, Substitution	n Method,						
Inequalities.							
Reasoning – a. Verbal - Blood Relation, Sense of Direction, Arithmetic & Alphabet.							
b. Non- Verbal reasoning - Visual Sequence, Visual analogy and classification.							
Analytical Reasoning - Single & Multiple comparisons, Linear Sequencing.							
Logical Aptitude - Syllogism, Venn-diagram method, Three statement syllogism, Dedu	uctive and						
inductive reasoning. Introduction to puzzle and games organizing information, parts of an	argument,						
common flaws, arguments and assumptions.							
Verbal Analogies/Aptitude – introduction to different question types – analogies, Gramm	nar review,						
sentence completions, sentence corrections, antonyms/synonyms, vocabulary building etc	c. Reading						
Comprehension, Problem Solving	I						
Unit - III							
	03 Hrs						
Interview Skills: Questions asked & how to handle them, Body language in interview, and	03 Hrs Etiquette –						
Interview Skills: Questions asked & how to handle them, Body language in interview, and Conversational and Professional, Dress code in interview, Professional attire and Grooming,	03 Hrs Etiquette – Behavioral						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice	03 Hrs Etiquette – Behavioral e on Stress						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews	03 Hrs Etiquette – Behavioral e on Stress						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV	03 Hrs Etiquette – Behavioral e on Stress 02 Hrs						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity	03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis	 03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender for brain 						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis storming; Group discussion(Assertiveness) and presentation skills	 03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender for brain 						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis storming; Group discussion(Assertiveness) and presentation skills Unit - V	 03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender for brain 07 Hrs 						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis storming; Group discussion(Assertiveness) and presentation skills Unit - V Motivation: Self-motivation, group motivation, Behavioral Management, Inspirati	 03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender for brain 07 Hrs ional and 						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis storming; Group discussion(Assertiveness) and presentation skills Unit - V Motivation: Self-motivation, group motivation, Behavioral Management, Inspirati motivational speech with conclusion. (Examples to be cited).	03 HrsEtiquette –Behaviorale on Stress02 Hrsy, genderfor brain07 Hrsional and						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis storming; Group discussion(Assertiveness) and presentation skills Unit - V Motivation: Self-motivation, group motivation, Behavioral Management, Inspirati motivational speech with conclusion. (Examples to be cited). Leadership Skills: Ethics and Integrity, Goal Setting, leadership ability.	 03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender for brain 07 Hrs ional and 						
Interview Skills: Questions asked & how to handle them, Body language in interview, and I Conversational and Professional, Dress code in interview, Professional attire and Grooming, I and technical interviews, Mock interviews - Mock interviews with different Panels. Practice Interviews, Technical Interviews, and General HR interviews Unit - IV Interpersonal and Managerial Skills: Optimal co-existence, cultural sensitivity sensitivity; capability and maturity model, decision making ability and analysis storming; Group discussion(Assertiveness) and presentation skills Unit - V Motivation: Self-motivation, group motivation, Behavioral Management, Inspirate motivational speech with conclusion. (Examples to be cited). Leadership Skills: Ethics and Integrity, Goal Setting, leadership ability.	 03 Hrs Etiquette – Behavioral e on Stress 02 Hrs y, gender for brain 07 Hrs ional and 						

CO1	Develop professional skill to suit the industry requirement.
CO2	Analyze problems using quantitative and reasoning skills

- **CO3** Develop leadership and interpersonal working skills.
- **CO4** Demonstrate verbal communication skills with appropriate body language.

Refer	ence Books:
1.	The 7 Habits of Highly Effective People, Stephen R Covey, 2004 Edition, Free Press, ISBN: 0743272455
2.	How to win friends and influence people, Dale Carnegie, 1 st Edition, 2016, General Press, ISBN: 9789380914787
3.	Crucial Conversation: Tools for Talking When Stakes are High, Kerry Patterson, Joseph Grenny, Ron Mcmillan 2012 Edition, McGraw-Hill Publication ISBN: 9780071772204
4.	Ethnus, Aptimithra: Best Aptitude Book, 2014 Edition, Tata McGraw Hill ISBN: 9781259058738

Scheme of Continuous Internal Examination (CIE)

Evaluation of CIE will be carried out in TWO Phases.

Phase	Activity					
I	After 9 hours of training program, students are required to undergo a test set for a total of 50 marks. The structure of the test will have two parts. Part A will be quiz based evaluated for 15 marks and Part B will be of descriptive type, set for 50 Marks and reduced to 35 marks. The total marks for this phase will be 50 ($15 + 35$).					
II	Similarly students will have to take up another test after the completion 18 hours of training. The structure of the test will have two parts. Part A will be quiz based evaluated for 15 marks and Part B will be of descriptive type, set for 50 Marks and reduced to 35 marks. The total marks for this phase will be $50 (15 + 35)$.					
	FINAL CIE COMPUTATION					
Continuo	bus Internal Evaluation for this course will be based on the average of the score attained through					
the two t	asts. The CIE score in this course, which is a mandatory requirement for the award of degree					
the two i	the two tests. The CIE score in this course, which is a mandatory requirement for the award of degree,					
must be	greater than 50%. Needless to say the attendance requirement will be the same as in any other					
course.						

Semester I						
ADVANCED COMPUTER ARCHITECTURE (Group A: Core Elective)						
Course Code	:	18MVE1A1		CIE Marks	:	100
Credits : L:T:P	:	4:0:0		SEE Marks	:	100
Hrs	:	48L		SEE Duration	:	3 Hrs
		Uı	nit — I			10 Hrs
Fundamentals Of C Introduction; Classe Integrated Circuits Quantitative Princip Computer Models- Computers, PRAM a	Con as o les Tho and	nputer Design of computers; Defining ad cost; Dependability of computer design. Pi e State of Computing, I VLSI Models.	g computer archite y; Measuring, rep peline and its haza Multiprocessors an	cture; Trends in Tec orting and summari rds; Implementation d Multicomputer, Mu	chnol izing of pi iltive	logy, Power in g Performance; ipeline; Parallel ector and SIMP
		Un	it – II			9 Hrs
Advanced Processon Processors RISC So VLIW Architecture Memory Technolog Technology- Virtua Cache Memory Org Associative and So Interleaved Memory	 Tecala y, N ani ector Or d N 	ar Processors. Supersca Vector and Symbolic I Inclusion, Coherence, Iemory Models, TLB, zations - Cache Addres or Caches and Cach ganization, Bandwidth Uni Multicomputer	and Locality Memory Processors. Memory and Locality Memory and Locality Memory and Segn sing Models, Direct and Fault Memory it – III	nstruction-Set Archite occessors Superscalar ry Hierarchy Techno hory Capacity Plannin nentation Memory Re ect Mapping and Asso ssues . Shared-Mem Allocation Schemes	Pro logy ng; V eplac ociat ory	es CISC Scalar cessors - The - Hierarchical Virtual Memory cement Policies ive Cache, Set- Organizations- 9 Hrs
Multiprocessor Syst Multistage and Con Coherence Problem Mechanisms. Three Development, The Deadlock and Virtua	Multiprocessor System Interconnects - Hierarchical Bus Systems, Crossbar Switch and Multiport Memory, Multistage and Combining Networks. Cache Coherence and Synchronization Mechanisms- The Cache Coherence Problem, Snoopy Bus Protocols, Directory-Based Protocols, Hardware Synchronization Mechanisms. Three Generations of Multicomputer - Design Choices in the Past, Present and Future Development, The Intel Paragon System. Message-Passing Mechanisms- Message-Routing Schemes, Deadlock and Virtual Channels Flow Control Strategies, Multicast Routing Algorithms.					
		Un	it – IV			9 Hrs
Multivector and SIMP Computers Vector Processing Principles- Vector Instruction Types, Vector-Access Memory Schemes Past and Present Supercomputers, Multivector Multiprocessors, Performance-Directed Design Rules Mainframes and Mini supercomputers, Compound Vector Processing -Compound Vector Operations, Vector Loops and Chaining, Multi pipeline Networking. SIMP Computer Organizations						
		Un	it – V			9 Hrs
Scalable, Multithree Latency-Hiding Tec Caches, Scalable Multithreading Issu Scalable and Multith	ad hni Co es rea	ed and Dataflow Archi iques - Shared Virtual herence Interface, Rel and Solutions, Mu ided Architectures, Data	tectures Memory, Prefeto axed Memory Con ltiple-Context Pro flow and Hybrid A	ching Techniques, D sistency, Principles cessor, Multidimensi rchitectures.	oistri of onal	buted Coherent Multithreading, Architectures,

Expected Course Outcomes:

After taking up this course, the graduate will be able to:

- CO1: Understand pipelining concepts, the performance metrics of microprocessors, Multithreading, multivector and dataflow architectures.
- CO2: Identify the factors affecting performance in superscalar processors and the key components, options and tradeoffs that a designer has to consider when designing such processors
- CO3: Evaluate the performance and efficiency in advanced multiple-issue processors.

CO4: Design various architectures and techniques for building high performance scalable multithreaded and multiprocessor systems.

Reference Books:

- 1.
 Kai Hwang, "Advanced Computer Architecture: Parallelism, Scalability, Programmability", McGraw-Hill, first edition, 1992.
- 2. Kai_Hwang,_Faye_A._Briggs, "Computer Architecture and parallel processing" McGraw-Hill, first edition, 1984.
- 3. Patterson, D.A., and Hennessy, J.L., "*Computer Architecture : A Quantitative Approach*", Morgan Kaufmann Publishers, 5th Edition, Inc.2011
- 4. Dezso Sima, Peter Kacsuk, Terence Fountain, "*Advanced Computer Architectures : A Design Space Approach*", Pearson Education India, 1997
- 5. Michael J Flynn, " *Computer Architecture: Pipelined and Parallel Processor Design* ", Narosa Publishing India, 2003

Continuous Internal Evaluation (CIE): Total marks: 100

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

				Semester I				
ASIC DESIGN (Group A: Core Elective)								
Course Code	:	:	18MVE1A2		CIE Marks	:	100	
Credits : L:T	:P :	:	4:0:0		SEE Marks	:	100	
Hrs	:	:	48L		SEE Duration	:	3 Hrs	S
			Uı	nit — I				10 Hrs
Introduction Types of ASI ASIC, Gate a Programmable Design flow.	to ASIC Cs: Full array bas e logic de	Cs Cu sec lev	istom ASIC, Semi-cusi 1 ASIC, Channeled g ices, FPGA.	tom based ASICS, ate array, Channel	Standard Cell based lless gate array, Strue	cture	d gate	array,
			Un	nit — II				10 Hrs
CMOS Logic Combination Data logic cel I/O Cell, Cell	al logic al logic lls: Data Compil	cel Pa	ls Sequential logic cel ath Elements, Adders, N s	ls: Latch, flipflop, Multipliers, Arithmo	clocked inverter. etic operator.(Practical	app	roach).	
			Un	it – III				9 Hrs
ASIC Librar Logical effor optimum dela Library cell de Programmat	ry Desig rt: predi ay, optim esign. ble ASIC	n icti nun CS:	ng delay, logical are n no. of stages. The Antifuse, Static F	a and logical effi	ciency, logical paths EEPROM technology	, mu	ulti sta	.ge cells,
			Un	it – IV		•		9 Hrs
Actel ACT: A Timing model Programmat Simulation. (F Low-Level D Icons & Sym place attribute	 Programmable ASICs logic cells Actel ACT: ACT1 logic module, Shannon's expansion theorem, Multiplexer logic as function generators, Timing models and critical path, speed gating, worst case timing. Programmable ASIC Design Software: Design System, logic synthesis, Introduction to Synthesis and Simulation. (Practical analysis of the design parameters for speed, area & power optimization). Low-Level Design Entry: Schematic Entry: Hierarchical design. The cell library, Names, Schematic, Icons & Symbols, Nets, schematic entry for ASIC'S, connections, vectored instances and buses, Edit in 							
•	*	,	Ur	nit — V				9 Hrs
ASIC Construction Floor Planning and Placement & Routing Physical Design, CAD Tools, System Partitioning, Estimating ASIC size, partitioning methods. Floor planning tools, I/O and power planning, clock planning, placement algorithms, iterative placement improvement, Time driven placement methods. Physical Design flow global Routing, Local Routing, Detail Routing, Special Routing, Circuit Extraction and DRC. Expected Course Outcomes:								
After taking u	p this co	our	se, the graduate will be	e able to:				
 After taking up this course, the graduate will be able to: CO1: Learn the issues involved in ASIC design, including technology choice, design management, tool-flow, verification, debug and test. CO2: Apply & analyze the design parameters for speed, area & power optimization. CO3:Develop the algorithms required for the design of ASIC. CO4: Apply the back-end physical design flow, including floorplanning, placement, and Routing techniques, Reference Books:								
1. M.J.S .S ISBN:97	mith, - " /8-81775	Ap 58-	oplication - Specific In 408-0	tegrated Circuits" -	- Pearson Education, 2	2003,	,	

2.	H. Bhatnagar, - "Advanced ASIC Chip Synthesis Using Synopsys Design Compiler Physical Compiler and PrimeTime", 2nd edition, 2001, ISBN:0792385373
3.	Farzad Nekoogar Farak Nekooga From ASICs-to-SOCs: A Practical Approach ISBN: 0-13-033857-5.
4.	P. Kurup, T. Abbasi, "Logic Synthesis Using Synopsys", ISBN 0-7923-9582-4
5.	D. J. Smith, "HDL Chip Design", ISBN 0-9651934-3-8

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester I								
ALGORITHMS FOR VLSI DESIGN (Group A: Core Elective)								
Course Code	:	18MVE1A3		CIE Marks	:	100		
Credits : L:T:P	:	4:0:0		SEE Marks	:	100		
Hrs	:	48L		SEE Duration	:	3 Hrs		
		U	nit — I			1	10 Hrs	
High Level Synthe Simple scheduling level modelling and Binary Decision D	e sis alg d si iagi	: Hardware models - Inte orithm - Assignment pro mulation - Switch-level : ram.	ernal representatio blem – High level modelling and sim	n - Allocation assignme transformations. VLS sulation - Combination	ent a [Sir al Lo	nd sched nulation: ogic Synt	luling - : Gate- thesis -	
		Un	nit — II			1	10 Hrs	
Data Structure a	nd	Basic Algorithms : Ba	sic Terminology,	Graph Search Algorit	hms	Comput	ational	
VLSI partitioning Group migration A Problem formulation simulated evolution	g& .lgo on, n fle	floor planning: Problective rithms, Simulated Anneat classification, Constraint por planning algorithms.	em Formulation, (aling and evolution based, Integer pro-	Classification of Partit n algorithm, other part ogramming based, rect	ioni itior angı	ng Algon ning algon nar duali	rithms, rithms. ization,	
		Un	it – III				9 Hrs	
Line Probe Algorit Problem formulation Clock and Power trees, Problem for Geometric matchin Dimensional Comp	hma on, o R o rmu ng oact	s, shortest path based Alg <u>Classification single Lay</u> <u>Un</u> outing : Design consider Ilation, Clock routing A based Algorithms. Con ion, Two-Dimensional C	gorithms, Steiner er routing, Genera it – IV ations for the clo Algorithms, H-tree paction: Classific compaction, Hierar	tree based Algorithms l river routing, Single r cking system, delay ca e based Algorithms, f ication of Compaction rchical Compaction.	De ow 1 alcui MM Al	tailed Ro routing. lation for M Algon gorithms,	9 Hrs 9 Hrs r clock rithms, , One-	
1		Ur	nit – V	· · · · · ·			9 Hrs	
Genetic algorithm algorithms ,steady Conventional algor and routing.	n a stat ithi	and its application in e algorithm – Genetic op ms – GA example – GA	VLSI physical of erators-types of G for VLSI design. (lesign : Terminologies A-Genetic algorithms Genetic algorithm in pa	– S vs rtior	Simple C	Genetic cement	
Expected Course	Ou	tcomes:						
After taking up this course, the graduate will be able to: CO1. Understand each stage of VLSI design flow. CO2. Apply design knowledge to develop algorithms for VLSI design automation. CO3. Investigate the algorithms for optimizing VLSI design with respect to speed, power and area. CO4. Create an optimized VLSI cell using various algorithms. Reference Books:								
1. S.H. Gerez, "	1. S.H. Gerez, "Algorithms for VLSI Design Automation", John Wiley & Sons, 1998, ISBN: 978-0-471-							
98489-4 2. N.A. Sherwar 2002, ISBN: 0	ni, ")-79	Algorithms for VLSI Phy 923-8393-1	ysical Design Auto	omation", Kluwar Acad	emi	c Publish	ners,	
3. Pinaki mazun automation",	ndei Pea	r and Elizabeth M Rudnie rson Edition, 2011.	ck, "Genetic algori	ithms for VLSI design	ayo	ut and tes	st	

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

			Semester I				
MEMS AND SMART SYSTEMS							
(Group B: Core Elective)							
	1	(Common	to VLSI & ES and	a CS)		100	
Course Code	:	18MVE1B1		CIE Marks	:	100	
Credits : L:T:P	:	4:0:0		SEE Marks	:	100	
Hrs	:	48L		SEE Duration	:	3 Hrs	S
		Uı	nit — I				10 Hrs
Introduction to M	EN	IS and principle of oper	ration.				
Introduction, Histo	ry o	of evolution, Definition of	of MEMS in a broad	der sense. Components	s of	a smar	t system.
Commercial produ	icts	. Microsystems and M	iniaturization. Evo	olution of micro-man	ufac	cturing.	. Design
Aspects. Application	on a	and future scope of MEM	S devices, Market t	rends.		-	_
Definitions and	sal	ient features of sens	sors, actuators a	nd systems. Worki	ing	princi	iples of
Microsystems.Sens	ors	: silicon capacitive acce	elerometer, piezo-re	esistive pressure sens	or,	blood	analyzer,
conductometric gas	s se	ensor, Actuators: silicon	micro-mirror arra	ys, piezo-electric base	ed in	nkjet p	rinthead,
electrostatic comb-	driv	ve and micromotor, magn	etic micro relay.				
		Un	it – II				10 Hrs
Micro and Smart	De	vices and Systems: Mate	erials and Processi	ing			
Materials							
Introduction, Subst	rate	es and Wafers, Active su	ibstrate materials, S	Si as a substrate mater	rial,	Si con	npounds,
Si Piezoresistors, C	fall	ium Arsenide, Quartz, Pi	ezoelectric Crystals	and Polymers.			
Processing		· 1·.1 1 .1 . C	1 1 1.		c	1 1	
Silicon water proc	ess	sing, lithography, thin-fi	Im deposition, etcl	hing (wet and dry), v	wate	er-bond	ling, and
metallization, Silic	con	micromachining: surfa	ice and bulk, bor	nding based process	TIO	ws. 11	nick-film
processing: Smart i	nat	erial processing, Emergin	ig trends.				0 Urs
	1.			11.			71115
Simplast deformab	linn	g and Scaling laws in M	licrosystems Mode	enng aanti a haam. Dimamh	off	aat Ma	ahaniaal
vibration: conoral	fe e	remulation Desonant V	ibration Design t	hent. a deam, billiorph	tora	ect, Me	domning
coefficients Basic	10	f fluid mechanics in ma	oro and mesoscale	S Capillary effect e	lect	anu ro-phoi	uamping resis and
Dielectrophoresis	5 0	i india incentantes in ind	ero and mesoscare	es, Capinary Chect, C	iccu	io-phoi	cois and
Scaling laws in Mi	nis	aturization					
Importance of sca	lin	g in MEMS- Scaling i	n geometry. Scali	ng in rigid body dy	nam	ics. so	caling in
electrostatic forces	. S	caling in electromagneti	c forces, scaling i	n electricity. scaling	in f	fluid d	vnamics.
scaling effects in th	e o	ptical domain. scaling in	biochemical pheno	omena.			J
0		Un	it – IV				9 Hrs
RF MEMS							
Introduction to RI	7 M	IEMS, Static Analysis of	of RF MEMS devi	ices: Spring Constant	of	Low-k	Beams,
Spring Constant of	C	antilever Beams, Spring	Constant of Circul	ar Diaphragms, Bear	n C	urvatui	re due to
Stress Gradients. E	lec	trostatic Actuation, Shap	e of the Deformed	Beam Under Electros	tatic	Actua	tion, DC
Hold-Down Voltag	ge	of MEMS Beams and	Cantilevers, Force	es on MEMS Beams	, Se	lf-Actu	uation of
MEMS Capacitive	Sw	itches, RF Hold-Down V	oltage of MEMS (Capacitive Switches.			
		Un	it – V				9 Hrs
Case study of dev	ice	s: Pressure sensors, accel	lerometers, micro p	oump, micro heater. Ir	ntroc	luction	to CAD
tool for simulation	of o	devices.	_	_			
Packaging : Integ	rati	on of Microsystems and	l microelectronics,	Packaging Introducti	on,	Micro	Systems
Packaging, Object	ive	s, Issues in packaging,	Special issues	in micro system pa	ckag	ging, 7	Types of
Microsystem Packa	iges	s, Packaging Technologi	es.				
Expected Course	Out	tcomes:					
After going throug	1 th	us course the student will	be able to:				

CO	O1 :Explain the technology to fabricate advanced micro- and smart systems							
CO2	CO2: Analyse different methods to fabricate MEMS devices.							
CO	3: Apply the basics of implementation of MEMS into products.							
CO4	4: Evaluate the principles and processes involved in the implementation of MEMS devices							
Ref	erence Books:							
1.	Dr. A.K.Aatre, Ananth Suresh, K.J.Vinoy, S. Gopala krishna, K.N.Bhat., "Micro and Smart Systems", John Wiley Publications, 2002, ISBN: 1118213904, 9781118213902							
2.	Tai-Ran Tsu, "MEMS & Microsystems: Design and Manufacture", Tata Mc-Graw-Hill.2002.8th reprint, ISBN-13:978-0-07-048709-3. ISBN-10:0-07-048709-X							
3.	RF MEMS Theory, Design and Technology GABRIEL M. REBEIZ. 2003A JOHN WILEY & SONS PUBLICATION. ISBN: 978-0-471-20169-4							
4.	S. D. Senturia, "Microsystems Design", Kluwer Academic Publishers, Boston, USA, 2001, ISBN 0-7923-7246-8							

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester I								
			SYSTEN	A ON CHIP DE	SIGN			
Course C	ode	:	(Group 18MVE1B2	b B: Core Elect	CIE Marks	:	100	
Credits :	L:T:P	•	4:0:0		SEE Marks		100	
Hrs		•	481		SEE Duration	•	3 Hr	5
		•	Ui	nit — I	SEE Durudon	•	0 111	10 Hrs
Unit – I Motivation for SoC Design: Introduction to SoC, SoB, SiP, Benefits of system-on-chip integration in terms of cost, power, and performance. Comparison on System-on-Board, System- on-Chip, and System-in-Package. Typical goals in SoC design – cost reduction, power reduction, design effort reduction, performance maximization. Productivity gap issues and the ways to improve the gap. System On Chip Design Process: Canonical SoC Design, SoC Design flow - waterfall vs spiral, Top-down vs Bottom up,Specification requirement, Types of Specification, System Design process, System level design issues- Soft IP vs Hard IP, Design for timing closure, Logic design issues- Verification strategy. On-chip buses and interfaces. Low Power Manufacturing								
test strateg	gies.		I In	;+ TT				10 Ung
Macro De Macro des Developin	esign Proc sign and V ng Hard I	cess erit Ma	:: Overview of IP Design fication. cros: Overview, Design of Hard Macros	n, Key Features, I Issues for Hard	Planning and Specificat Macros, The Hard Mac	ion, ro D	esign	10 115
riocess, r	Touuctizat	.1011	Un	it – III				9 Hrs
SoC Verif languages, VLSI Pac design.	fication:-V Verificati kaging: I	Ver on ntro	fication technology opt IP Reuse, approaches. V duction, Packaging, Po	ions, Verification Verification and I wer Distribution,	n methodology, Verifica Device Test, Verificatio Input/Output, Chip-Pa	tion n Pla ckag	nns. e Co-	
			Un	it – IV				9 Hrs
Interconn (NOC) top routing.	ect archi pologies. N	tect Mes	tures for SoC. Bus arch h-based NoC. Routing i	itecture and its li n an NoC. Packe	mitations. Network on (t switching and wormho	Chip ole		
			Un	it – V				9 Hrs
MPSoCs: flexibility Processor,	What, Wl for MPSo The impa	hy, Cs act o	How MPSoCs, Techniq design: The limitations of SoC integration.	ues for designing of traditional AS	g MPSoCs, Performance IC design, General Purp	e and bose		
Expected	Course C	Dute	comes:					
After goin	g through	thi	s course the student will	be able to:				
 CO1: Learn about the system on chip design and macro design process. CO2: Analyze the design flow, IP cores, routing used in system on chip . CO3: Exposure the concepts of verification methodology and interconnection methods in SoC CO4: Design & Develop the algorithms required for the design of IP and SoC and Exposure to the cor of MPSoCs. 							concept	
Reference Books:								
1 Michael Keating, Pierre Bricaud, Reuse Methodology manual for System-On-A-Chip								
Desig	gns,Kluwe	er A	Cademic Publishers, sec	ond edition,2001	Varification Mathadalaa	11.00	4	
Z Praka	niques, K	luw	er Academic Publishers	,2001.	ermeanon-methodolog	y an	u	
3 A.A.	Jerraya, W	V.W	Volf, Multiprocessor Sys	tems-on-chips, 1	st Edition,Morgan Kaul	fman	n, 2004	ŀ

4	Sudeep Pasricha and Nikil Dutt,"On-Chip Communication Architectures: System on Chip
	Interconnect", Morgan Kaufmann Publishers © 2008.
5	Rao R. Tummala, Madhavan Swaminathan, "Introduction to system on package sop- Miniaturization
	of the Entire Syste", McGraw-Hill, 2008.
6	Neil H E Weste, David Harris, Ayan Banerjee, "CMOS VLSI Design", Third edition Pearson
	Education, ISBN: 0321149017

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester I									
ADVANCED VLSI DEVICES									
Course Code	:	18MVE1B3	J D. Core Electiv	CIE Marks	:	100			
Credits : L:T:P	:	4:0:0		SEE Marks	:	100			
Hrs	:	48L		SEE Duration	:	3 Hrs			
	Unit – I 10 Hrs								
MOSFET Device Metri Theory, The "Virtual Se MOS Electrostatics : In Voltage, Mobile Charge	cs, 1f ource ntrodu e: Bul	ansistors to Circu Model". ction, Depletion A <u>k MOS, Mobile C</u> Un	Approximation. Gat harge: ETSOI, 2D iit – II	ew of Transistors, Tr e Voltage and Surface Electrostatics, The VS	e Pot	ential, Flatband del Revisited 10 Hrs			
Short Channel Effects challenges to further Ch	and MOS 1	Challenges to CM miniaturization	IOS : Short channel	l effects, scaling theor	y, pr	ocessing			
		Un	it – III			10 Hrs			
Beyond CMOS: Evolution Evolution and biologic tolerant computing	utiona cal co	ry advances beyo mputing Mole el	ond CMOS, conver ectronics-molecula	ntional vs. tactile cor r Diode and diode-	nputi diod	ng, computing, e logic. Defect			
		Un	it – IV			9 Hrs			
The Transmission The Transmission Theory of and Limitations	eory of the N	of the MOSFET: MOSFET, Connec	Introduction, Trans tion to the VS Mod	mission, MFP and Di lel, Analysis of the Ex	ffusi	on Coefficient, nents, Limits			
			$\frac{\mathbf{nt} - \mathbf{V}}{\mathbf{nt} - \mathbf{V}}$			9 Hrs			
Advanced CMOS: Ner FETs, Nanotube FETs (Excitons, Spin, Phase)	w Mat s, Nar Fransi	terials and Device nowire FETs, No tions)	Structures (CMOS vel steep subthres	shold slope devices,	ETs, Alte	Heterostructure rnative devices			
Expected Course Oute	comes	: so the student will	ba abla to:						
 After going through this course the student will be able to: Describe the physics of semiconductor, basic theory of Metal Semiconductor Contacts and PN junction, MOS & transport mechanism Apply the VLSI device paraemetrs and calculate the device performance Analyze various modern VLSI devices & & compare its performances with MOS devices Evaluate or design the transport mechanism and modelling for emerging devices Reference Books: 									
1. Advanced Semiconductor Fundamentals, 2nd Edition, R. F. Pierret, Prentice Hall, ISBN No. 0-13-									
061792-X.2.Fundamentals of M University Press, 2	 061792-X. Fundamentals of Modern VLSI Devices, 2nd Edition, Yuan Taur and Tak H. Ning, Cambridge University Press, 2009, ISBN No. 9780521832946. 								
3. Kevin F Brennan Applications", Car	,"Intro mbrid	oduction to Semic ge University Pres	conductor Devices: ss; 1 edition,, ISBN	For Computing and No. 978-052183150	Felec 5	communications			
4. Y.P. Tsividis, Col Univ Press,2014,	in Mc ISBN:	Andrew "Operation 978-0195170153	on and Modeling of	f the MOS Transitor",	3 rd	Edition, Oxford			

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester II							
ANALOG IC DESIGN							
Course Code	:	18MVE21		CIE Marks	:	100+	50
Credits : L:T:P	:	3:1:1		SEE Marks	:	100+	50
Hrs	:	48L+36P		SEE Duration	:	3 Hr	s
		Uı	nit – I		L		10 Hrs
MOS transistors:	Co	mponents available in a	CMOS process, N	MOS small signal mo	dels	, conce	ept of f _{T,}
noise model.	~						
Single stage Ampli	fie	rs: Basic concepts, dc a	nalysis, small signa	al analysis and noise a	inaly	sis of	common
source and common	ga iifi	ite stage, power, bandwi	ath, impedance and	a frequency scaling of	circ	uits, F	requency
Current Mirror [•] B	asio	c Current Mirrors Casco	ode current Mirrors	amplifiers biased at c	onst	ant cui	rrents
	uor	Un	it – II	, unipilitets stased at e	onst	unt ou	9 Hrs
Differential Amplif	Ter	s. Single ended and diff	Ferential operation	Common mode respon	nse	differe	ntial nair
with active loads. G	ilbe	ert cell	creman operation,	common mode respon	150,	unitere	iniai pan
Operational Ampl	ifie	r: One stage op-amp,	two stage op-amp,	Telescopic Cascode	opa	mp, To	elescopic
Cascode opamp fre	equ	ency response, Folded	Cascode opamp-d	lc gain, Telescopic a	nd f	folded	Cascode
opamp-noise, mism	atc	ch, slew rate, Two sta	age opamp-topolog	gy, frequency respor	nse,	gain	boosting,
common mode feed	bac	k.					
		Un	it — III				10 Hrs
Noise: Resistors, M	OS	FET, Input and output r	referred noise, noise	e scaling, basic amplif	ier s	stages -	– CS and
CG stage							
Feedback: Non-ide	alit	ies- finite dc gain, effec	t of additional pole	s & zeros, feedback to	polo	ogies, s	ense and
return mechanisms,	eff	fect of loading, effect o	f feedback on nois	se, feedback circuit a	nalys	sis usii	ng return
ratio – closed loop g	aın	and impedance using re	eturn ratio				0.11
Stability analysis a	nd		<u>II — IV</u> tions Stability of T	Jaadhaalu Dagia Cona	anto	Instak	9 Hrs
the Nyquist Criterio	na n	Frequency Compensation	n: Concepts and T	echniques for Frequen	epis,		ninty and
Dominant pole Mill	n. er	Compensation	in. Concepts and To	echniques for Frequen	icy (Joinpe	iisation –
Band gap reference	e: E	Band gap reference. Con	stant current and co	onstant gm bias genera	tors.	reduci	ing
supply sensitivity		8 1		6 6	,		0
Low dropout regul	ato	rs: Basic requirements	and constraints				
		Un	nit – V				9Hrs
Phase Locked Loo	ps	: Simple Phase locked l	loop, Charge pump	PLL, Non-ideal effect	cts -	Jitter	& Phase
noise, Applications		_					
Analog Layout tech	nni	ques: General layout co	nsiderations – desig	gn rules, antenna effec	et, la	yout te	chniques
for multi finger transistors, symmetry, reference distribution, passive devices, interconnects, Electro static							
discharge (ESD) protection, substrate coupling							
Lab Component							
1. Study of DC and small signal models of a MOS Transistor							
2. Design of MOS current sources and mirrors							
3. Design of si	ngl	le stage amplifiers $-CS$	Amplifter with diff	erent loads			
4. Design of a	1/1	JS Differential amplifier	r with an active loa	u			
5. Design of a		scoue amplifier, double	cascode and triple	cascode amplifier			
0. Design of 1		scopic opanip					
7. Design of a	∠-S	age CMOS Op-Amp					

8. Design of Band Gap Reference circuit
9. Post-layout simulation of any two circuits
Expected Course Outcomes:
After going through this course the student will be able to:
CO1: Define & demonstrate device, circuit & system aspects of analog IC design
CO2: Analyze the functionality of analog circuits & systems
CO3: Design and implement analog integrated circuits & systems
CO4: Evaluate the different performance parameters of analog integrated circuits & systems
using CAD tools.
Reference Books:
1. Behzad Razavi, "Design of Analog CMOS Integrated Circuits", Mc GrawHill Edition, 2002, ISBN: 0- 07-238032-2
2. R. Jacob Baker, Harry W. Li and David E. Boyce, "CMOS Circuit Design, Layout and Simulation", IEEE Press, 2002, ISBN: 81-203-1682-7
Grav, Hurst, Lewis, and Meyer: "Analysis and design of Analog Integrated Circuits", (4/e), John
Wiley & Sons, ISBN-10: 0470245999
4. Phillip E. Allen and Douglas R. Holberg, "CMOS Analog Circuit Design", (2/e)
Oxford University Press, February 2002, ISBN: 9780199765072
5. David Johns and Ken Martin, "Analog Integrated Circuit Design", John Wiley & Sons, Inc., 1997,
ISBN-10: 0470770104

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Scheme of Continuous Internal Evaluation (CIE) for Practicals: (50 Marks)

The Laboratory session is held every week as per the time table and the performance of the student is evaluated in every session. The average of marks over number of weeks is considered for 30 marks. At the end of the semester a test is conducted for 10 marks. The students are encouraged to implement additional innovative experiments in the lab and are rewarded for 10 marks. Total marks for the laboratory is 50.

Semester End Evaluation (SEE): Total marks: 100+50=150

Theory (100 Marks) + Practical (50 Marks) = Total Marks (150)

Scheme of Semester End Examination (SEE) for 100 marks:

The question paper will have FIVE questions with internal choice from each unit. Each question will carry 20 marks. Student will have to answer one full question from each unit.

Scheme of Semester End Examination (SEE); Practical (50 Marks)

SEE for the practical courses will be based on experiment conduction with proper results, is evaluated for 40 marks and Viva is for 10 marks. Total SEE for laboratory is 50 marks.

	Semester II							
SYSTEM VERILOG FOR DESIGN AND VERIFICATION								
Course Code	:	18MVE22		CIE Marks	:	100		
Credits : L:T:P	:	3:1:0	-	SEE Marks	:	100		
Hrs	:	48L		SEE Duration	:	3 Hrs		
		Uı	nit – I				10 Hrs	
Introduction to SystemVerilog stand Verilog over Verilog byte, shortint, int, lo Struct data types, Str Dynamic Arrays, M Tasks and Function Statement, Passing A	Introduction to SystemVerilog: SystemVerilog standards, Key SystemVerilog enhancements for hardware design.Advantages of System Verilog over Verilog, Data Types: Verilog data types, System Verilog data types, 2 - State Data types, Bit, byte, shortint, int, longint. 4 - State data types. Logic, Enumerated data types, User Defined data types, Struct data types, Strings, Packages, Type Conversion: Dynamic casting, Static Casting, Memories: Arrays, Dynamic Arrays, Multidimensional Arrays, Packed Arrays, Associative Arrays, Queues, Array Methods, Tasks and Functions: Verilog Tasks and Functions, Enhancements in S.V, Void Functions, Return Statement, Passing Arguments, Arguments Passing by Name. Default Arguments. Passing Arguments by							
value, Passing Argu	ments	by Reference.	nit – II				10 Hrs	
Connecting the Test	tbenc	h and Design:						
SystemVerilog port Interface References Scheduler, Clocking	conn conn , Tas Blocl	ections, Interface in ks and functions in k, Input and Output S	stantiation 2 interface, V Skews, Typic	2.4. Interfaces Arguverilog Event Sche al Testbench Enviro	Syster uments, eduler, onment,	mverilog Interface SystemVeri Verificatio	Modports, log Event n plan	
		Un	it – III				9 Hrs	
OOPs Basics and A	dvan	ced OOPs concepts:						
Basic OOP Concept	ts							
Overview of Classes Null Object handler Copying an Object: S Advanced OOP Con	s, Pro s, Ac Shallo ncept	perties and Methods ccessing Members, t ow Copy, Deep Copy s heritance Super Kat	in the Class this Keywor	ses, Instance/Object d, Creating an O	t Creation bject, C	on, New Co Objects Ass	onstructor, signments,	
- \$cast Virtual Class	es Pa	arameterized Classes	yworu, Static	properties, Overne	ing we	chious, Poly	morpinsm	
quality vintual Class		Un	it – IV				9 Hrs	
Constrained Rando	miza	tion, Threads and In	nter-process	Communication:				
Constrained Randomization Random Variables - rand and randc, Randomize() Method - Pre/Post Randomize() methods, Constraints in the class, Rand_mode and constraint_mode, Constraint and Inheritance, Constraint Overriding, Set Membership, Distribution Constraints, Conditional Constraintsimplication (->), if/alca_Inline Constraints								
. II/CISC, IIIIIIC CONSULATION								
Threads, Fork-Join/Join_any/Join_none, Communication – Mailbox, Semaphore, Events, BuildingaTestbenchwithThreadsandIPC								
Unit – V 9 Hrs								
Functional Cover	age	andAssertion Bas	sed Verific	ation:			1	
Functional Coverag	ge –							
Coverage Definition	, Cod	e Coverage, Function	nal Coverage	: Cover Group, Crea	ating Co	over Group	Instances,	

Coverpoints, Bins - . implicit bins, . Explicit bins, Bin creation, Vector and Scalar bins, Cross products, Intersect, Select Expressions, Conditional Expression (iff), Illegal bins, Ignore bins, Coverage Analysis, Covergroup Built-in Methods - . Sample(), . get_coverage(), .get_instance_coverage(), .set_instance_name(string), .start(), . stop()

Assertion Based Verification

Introduction, Types of Assertions - . Immediate, . Concurrent, Assertion Properties- . Writing Properties, Sequences- . Sequence Composition, . and, or, intersect, Advanced SVA Features - Expect, Binding, Assertion Coverage

Expected Course Outcomes:

After taking up this course, the graduate will be able to:

CO1: Demonstrate the use of System Verilog data types for digital system design and functional verification.

CO2: Demonstrate the skill on writing test-benches for design of digital systems and connecting them with the design.

CO3: Verify and Analyze the complete systems through robust verification methods such as assertion based verification.

CO4: Design and verify the digital systems such as FIFOs, memories, ATM interfaces, etc. using the learnt methods and demonstrate the skills.

Reference Books:

1.	Stuart Sutherland, Simon Davidmann and Peter Flake, "SystemVerilog for Design - A Guide to Using
	SystemVerilog for Hardware Design and Modeling," 2E, Springer Science, ISBN-13: 978-0387-3339-
	91, 2006.

- 2. C Spear, "SystemVerilog for Verification-A Guide to Learning the Testbench Language Features," Springer Science, IEEE press, ISBN-13: 978-0387-2703-64,2006.
- 3. Doulos, "SystemVerilog golden reference guide-A concise guide to SystemVerilog IEEE Standard-1800-2009," Version 5.0,ISBN: 0-9547345-9-9, 2012.
- 4. Sasan Iman, "Step-by-Step Functional Verification with SystemVerilog and OVM," Hansen Brown Publishing Company,ISBN-13: 978-0-9816-5621-2, 2008.

5. IEEE Computer Society, "IEEE Standard for SystemVerilog-Unified Hardware Design, Specification and Verification," IEEE Press, ISBN: 978-0-7381-6129-7, 2009

Continuous Internal Evaluation (CIE): Total marks: 100

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

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Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

	Semester II							
RESEARCH METHODOLOGY								
Course Code	:	18IM23		CIE Marks	:	10	0	
Credits : L:T:P	:	3:0:0		SEE Marks	:	10	0	
Hrs	:	36L		SEE Duration	:	3	hours	
		Uni	it – I			1	07 Hrs	
Overview of Resear to different research design, completely ra	ch: Re design andom	esearch and its type ns. Essential constit ized, randomized bl	es, identifying and tuents of Literature ock, Latin Square,	defining research pro e Review. Basic prir Factorial.	oblem	and of	introduction experimental	
		Uni	t – II				08 Hrs	
Data and data collect Primary data and Sec designing questionna Sampling Methods:	ction: condar ires ar Proba	Overview of probat y Data, methods of ind schedules. bility sampling and	primary data type primary data colled Non-probability sa	ss ction, classification o ampling	f seco	ndar	ry data,	
		Unit	t – III				07 Hrs	
Advanced statistica	is Tes	t Data: Statistical n ting and ANOVA. I Unit yses: Non paramet	neasures of location interpretation of ou t - IV ric tests, Introduct	n, spread and shape, (tput from statistical s tion to multiple regr	correl oftwa	re to	n and ools 07 Hrs ctor analysis,	
cluster analysis, prin software tools.	cipal	component analysis	s. Usage and interj	pretation of output f	rom s	tatis	tical analysis	
		Un	it-V				07 Hrs	
Essentials of Report Writing Report, Layo Case studies: Di	t writi	ng and Ethical issu the Research Report ion of case studi	t , Ethical issues re es specific to t	f Report Writing, Di lated to Research, Pu he domain area o	fferen blishi f spe	t Ste ng, I cial	eps in Plagiarism. ization	
After going through	this co	urse the student wil	l be able to					
CO1: Explain the pri	nciple	s and concepts of re	search types, data	types and analysis pr	ocedu	res.		
CO2: Apply appropr	iate m	ethod for data collect	ction and analyze the	he data using statistic	al pri	ncip	les.	
CO3: Present researc	h outp	out in a structured re	port as per the tech	nnical and ethical star	ndards	5.		
CO4: Create research	ı desig	n for a given engine	eering and manage	ment problem situation	on.			
Reference Books:								
1) Kothari C.R., Re edition, ISBN: 9	search 78-93-	Methodology Meth 86649-22-5	nods and technique	es by, New Age Intern	nation	al Pı	ublishers, 4th	
2) Krishnaswami, K Pearson Educatio	K.N., S on: Ne	ivakumar, A. I. and w Delhi, 2006. ISBI	Mathirajan, M., M. N: 978-81-77585	Ianagement Research -63-6	Meth	odo	logy,	
3) Levin, R.I. and F	Rubin,	D.S., Statistics for N	Management, 7th E	Edition, Pearson Educ	ation:	Nev	w Delhi.	
Continuous Interna	l Eval	uation (CIE): Tota	nl marks: 100					

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II							
MINOR PROJECT							
Course Code	:	18MVE24		CIE Marks	:	100	
Credits L: T: P	:	0:0:4		SEE Marks	:	100	
Credits	:	02		SEE Duration	:	3 hrs	

GUIDELINES

- 1. Each project group will consist of maximum of two students.
- 2. Each student / group has to select a contemporary topic that will use the technical knowledge of their program of study after intensive literature survey.
- 3. Allocation of the guides preferably in accordance with the expertise of the faculty.
- 4. The number of projects that a faculty can guide would be limited to four.
- 5. The minor project would be performed in-house.
- 6. The implementation of the project must be preferably carried out using the resources available in the department/college.

	Course Outcomes: After completing the course, the students will be able to							
CO1	Conceptualize, design and implement solutions for specific problems.							
CO2	Communicate the solutions through presentations and technical reports.							
CO3	Apply resource managements skills for projects.							
CO4	Synthesize self-learning, team work and ethics.							

Scheme of Continuous Internal Examination

Evaluation will be carried out in 3 phases. The evaluation committee will comprise of 4 members: Guide, Two Senior Faculty Members and Head of the Department.

Phase	Activity	Weightage
Ι	Synopsys submission, Preliminary seminar for the approval of selected topic and	20%
	objectives formulation	
II	Mid term seminar to review the progress of the work and documentation	40%
III	Oral presentation, demonstration and submission of project report	40%
deale 701		

** Phase wise rubrics to be prepared by the respective departments

CIE Evaluation shall be done with weightage / distribution as follows:

٠	Selection of the topic & formulation of objectives	10%
•	Design and simulation/ algorithm development/ experimental setup	25%
•	Conducting experiments/ implementation / testing	25%
٠	Demonstration & Presentation	15%
٠	Report writing	25%

Scheme of Semester End Examination (SEE):

The evaluation will be done by ONE senior faculty from the department and ONE external faculty member from Academia / Industry / Research Organization. The following weightages would be given for the examination. Evaluation will be done in batches, not exceeding 6 students.

•	Brief write up about the project	05%				
•	Presentation / Demonstration of the Project	20%				
•	Methodology and Experimental results & Discussion	25%				
•	Report	20%				
•	Viva Voce	30%				
			Semester II			
--------------------------------	-----------	--------------------------	------------------------	--------------------------	----------------	------------------
		V	LSI TESTING	、 、		
		(Group	C: Core Electiv	ve)	T	100
Course Code	:	18MVE2C1		CIE Marks	:	100
Credits : L:T:P	:	4:0:0		SEE Marks	:	100
Hrs	:	48L		SEE Duration	:	3 Hrs
			nit - 1	1 66 1 1 1		9 Hrs
Introduction to Testing	g: K	Cole of testing VLSI	circuits, VLSI trer	ids affecting testing, I	hysi Dal	cal Faults,
Fault Modeling - Functi	ons	raults, Permanent,	1 Testing Types of	Fault Models Stuck	, Del at Fa	lay raults.
Faults cross point faults	F:	ault Fouivalence Fa	ault Dominance	1 auti Wiodels, Stuck-	at 1 7	iuns, bridging
1 duits, cross point radits	, 1 (iun Equivalence, i c				
		Un	nit — II			9 Hrs
Testability Measure – (Cor	trollability, Observ	ability, SCOAP me	easures for combination	nal a	and sequential
circuits.						
ATPG for Combinat	ion	al Circuits: Path	Sensitization Me	ethods, Roth's D-	Algo	rithm, Boolean
Difference, PODEM Alg	gori	thm. Complexity of	f Sequential ATPG	, Time Frame Expans	ion.	40.77
		Un	it – III			10 Hrs
Design for Testability-	A	d-hoc, Structured L	DFT- Scan method	, Scan Design Rules,	Ove	erheads of Scan
Design, partial scan met	100 14	is, multiple chain sc	an methods.	allal Daduative and		East
Fault Simulation- Fa	un	Simulation algori	lunin- Serial, Para	allel, Deductive and		Incurrent Fault
Boundary Scan Standa	rd	TAP Controller 7	Past Instructions			
Doundary Scan Standa	Iu	<u>IAI Controller, I</u>	it _ IV			10 Hrs
Self test And Test Algo	ritl	hms				10 1115
Built-In self-Test, test p	atte	rn generation for B	IST, response com	paction - Parity checl	cing.	Ones counting.
Transition Count, Signat	ure	analyzer.Circular I	BIST, BIST Archite	ctures.	0,	6,
Testable Memory Desig	gn	Test Algorithms, F	Reduced Functiona	l Faults-MARCH and	1 M.	AT+ algorithm.
Test generation for Emb	edc	led RAMs.				C
		Un	nit — V			10 Hrs
Fault Diagnosis						
Logical Level Diagnosis	, D	iagnosis by UUT re	duction, Fault Diag	gnosis for Combinatio	nal (Circuits, Self-
checking design, System	Le	evel Diagnosis.				
CO1. Acquire knowle	dge	about fault modeling	ng & collapsing.			
CO2. Analyse various	co	mbinational ATPG	techniques			
CO3. Evaluate the sign	nifi	cance of sequential	test pattern generat	tion		
CO4. Develop fault si	mu	lation techniques &	fault diagnosis me	thods		
Reference Books:						
1. CO5. Michael I	L.B	ushnell, Vishwani	D. Agrawal, "Ess	entials of Electronic	Tes	ting for Digital
Memory &	εN	lixed Signal VLSI (Circuits", Kluwer A	Academic Publications	, 199	99.
2. CO6. MironAbr	am	ovici, Melvin A. B	Breuer, Arthur D. I	Friedman, "Digital S	yste	ms Testing and
Testable I)esi	ign", 3rd Edition, Ja	uico Publishing Hou	use, 2004		
3. CO7. Hideo Fu	iw	ara, " Logical testin	g & design for test	ability", The MIT Pre	ss.	
4. CO8. Parag.K.L	ala	"Digital Circuit Te	sting and Testabilit	y" Academic Press.		

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2)

seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100 Scheme of Semester End Examination (SEE) for 100 marks:

			Semester II						
			MACHINE LEARNIN	G					
(Group C: Core Elective)									
			(Common to VLSI & ES, CS, CNE,	D	CE, BMI, SE)		1		
Cou	rse Code	:	18MCS2C2		CIE Marks	:	: 100		
Cre	dits : L:T:P	:	4:0:0		SEE Marks	:	100		
Hrs		:	48L		SEE Duration	:	3 Hrs	5	
			Unit – I					9 Hrs	
Intr Line Stoc regr	Introduction: Overview of Probability Theory, Model Selection, Introduction to Machine learning. Linear Regression – Basis Function models, Bias Variance Decomposition, Bayesian linear Regression; Stochastic gradient Descent, Discriminant Functions, Bayesian Logistic regression. Examples on linear regression, logistic regression								
			Unit – II					10 Hrs	
Sup Kerr	ervised Learning nel Methods: Dual	rej eth	presentations, Construction of a kernel,	Ra	adial Basis Function	Netv	vorks, (Gaussian	
Spai	se Kernel Machine	eu es:	Maximum margin classifiers (SVM). R	V	M.				
Exa	mples on spam, mi	xe	r and k nearest neighbour						
	• •		Unit – III					10 Hrs	
Mix mixt Mar	ture Models: K-r tures, The EM Alg ket booklet analysi	ng ne gor .s	ans Clustering, Mixtures of Gaussians ithm in General, Principal Component	s,] Ai	Maximum likelihoo nalysis, Probabilistio	d, El c PC	M for (A, Exar	Gaussian nples on	
			Unit – IV					10 Hrs	
Ran Intro Importhe I	dom Forests: oduction, Definition ortance, Proximity De-Correlation Effo	on Pl ect	of Random Forests, Details of Ra ots, Random Forests and Over-fitting, Bias, Adaptive Nearest Neighbors.	ano A	dom ,Out of Bag nalysis of Random I	Sam	ples , ts, Vari	Variable ance and	
			Unit – V					9 Hrs	
Ensemble Learning: Introduction, Boosting and Regularization Paths, Penalized Regression, The "Bet on Sparsity" Principle, Regularization Paths, Over-fitting and Margins, Learning Ensembles, Learning a Good Ensemble, Rule Ensembles									
Exp	ected Course Out	co	mes:						
CO1	: Explore the basic Algorithms.	is c cs c	of Probability, data distributions and net	ura	al networks				
CO2	2: Apply the variou Application.	S C	limensionality reduction techniques and	l le	earning models for the	ne giv	ven		
CO_2	: Analyze the diffe	sif	ication and regression algorithms for give	i it ve	n data set				
Ref	erence Books:	511	reation and regression argorithms for gr	10	ii dutu set.				
1	Christopher M D	٥ĥ	on: Dattern Dessention and Mashing L	0.01	mina Chrinaan Fab		w 2006	ICDN	
1.	10: 0-387-31073-	<u>8,</u>	ISBN-13: 978-0387-31073-2.		rning, springer, re u		y 2000	19DIN-	
2.	Springer, 2008.		rt 110shirani, and Jerome Friedman: Th	e	Elements of Statistic	ai Le	arning,	_	
3.	Jiawei Han and M Kaufmann, 2006,	lic IS	heline Kamber: Data Mining – Concept SBN 1-55860-901-6	s a	and Techniques, Thi	rd Ec	lition, N	Aorgan	
4.	Zumel, N., & Mo ISBN 978161729	un 15	t, J. "Practical data science with R", Ma 62	nr	ning Publications, 20)14,			

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

	Semester II						
HIGH SPEED VLSI DESIGN							
Cou	rse Code	:	(Grouj 18MVE2C3	CIE Marks	:	100	
Cre	dits : L:T:P	:	4:0:0	SEE Marks	:	100	
Hrs		:	48L	SEE Duration	:	3 Hr	s
			U	nit – I			10 Hrs
Intr Capa wire LC t	oduction to high spacitance and inducta s, geometry and ele transmission lines, lo	peed ance ctric ossy	l digital design: H effects, high spec cal properties of w RLC transmission	Frequency, time and distance issues in d ed properties of logic gates, speed and p vires, Electrical models of wires, transmi lines and special transmission lines.	igita owe ssio	l VLS er. Mo n lines	I design. deling of , lossless
	10 / 01 /0		Ur				10 Hrs
Pov On-o digit	thip bypass capacit tal systems, power su	d N ors uppl	oise: Power suppl and symbiotic by y noise, crosstalk a	y network, local power regulation, IR d pass capacitors. Power supply isolation and inter symbol interference. Power distr	rops . No ibut	, area pise so ion on	bonding. ources in chips.
			Un	it – III			9 Hrs
Sign trans sign	aling convention smission media, signaling terminations, tr	and nalii rans	circuits: Signaling over RC intercontent intercontent of the second seco	ng modes for transmission lines, sign connect, driving lossy LC lines, simultar c circuits.	aling neou	g over s bi-d	· lumped irectional
			Un	it – IV			9 Hrs
Cloo Non Cloo	cked & non clocked clocked Logic Styl cked Logic Styles:Si	Lo es: S ingl	gics: Static CMOS, DCV e-Rail Domino Log	VS Logic, Non-Clocked Pass Gate Famili gic, Dual-Rail Domino Structures	es		
			Ur	nit – V			10 Hrs
Late Basi char Exp	ching Strategies: c Latch Design, and ged Logic Asynchro ected Course Outco	d La nou ome	tching single-ende s Latch Technique s:	ed logic and Differential Logic, Race Fr s, DDR memories.	ee L	atches	for Pre-
Δfte	r taking up this cour	se t	he graduate will be	a shle to:			
COI	Investigate the spec	cial 1	requirements that a	are imposed on high speed digital design.			
CO2	Analyze the charac	teris	tics of transmissio	n lines and high speed latches and circuits	5.		
CO3	Analyze the Signal	ing	convention in trans	smission media and high speed digital log	ics.		
CO4	Evaluate the perfor	mar	ce of various trans	mission lines and high speed digital circu	its.		
Refe	erence Books:						
1.	William S. Dally & 1998. ISBN 0-521-	: Joł 592	n W. Poulton, "Di 92-5	gital Systems Engineering", Cambridge U	Jniv	ersity]	Press,
2.	 Kerry Bernstein, Keith M. Carrig, Christopher M. Durham, Patrick R. Hansen, David Hogenmiller, Edward J. Nowak, Norman J. Rohrer., "High Speed CMOS Design Styles", Kluwer Academic Publishers in 1999. ISBN 978-1-4613-7549-4. 						
3.	Masakazu Shoji, "1 978-0201634839.	Hig	n Speed Digital C	ircuits", Addison Wesley Publishing Con	npa	ny, 19	96. <i>ISBN</i>
4.	Howard Johnson & Prentice Hall PTR,	: Ma 199	rtin Graham, "Hig 3.	h Speed Digital Design" A Handbook of	Blac	k Mag	ic,
5.	Jan M.Rabaey, Ana Perspective", (2/e),	nth Pe	a Chadrakasan, Bo arson 2016, ISBN-	rivoje Nikolic, "Digital Integrated Circuit 13: 978-0130909961.	s: A	Desig	n

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

			Semester II				
		LOW PC)WER VLSI DESIGN n D : Core Elective)				
Course Code	:	18MVE2D1	CIE Marks	:	100		
Credits : L:T:P	:	4:0:0	SEE Marks	:	100		
Hrs	:	48L	SEE Duration	:	3 Hrs	5	
		Uı	nit – I			10 Hrs	
Introduction and A Introduction: Need Emerging Low pow Algorithm Level lo	Introduction and Algorithm Level Low power Methods: Introduction: Need for low power VLSI chips, Sources of power dissipation on Digital Integrated circuits. Emerging Low power approaches, Physics of power dissipation in CMOS devices. Algorithm Level low power Methods: Introduction, design flow, Algorithmic level analysis & optimization.						
Davias & Technol	0.07	Impost on Low Dowon				10 1115	
Dynamic dissipation Technology & Dev	on i ice	in CMOS, Transistor siz	• sing & gate oxide thickness, Impact of t	echı	nology	Scaling,	
		Un	it – III			9 Hrs	
Power estimation methods Simulation Power analysis: SPICE circuit simulators, gate level logic simulation, capacitive power estimation, static state power, gate level capacitance estimation, architecture level analysis, data correlation analysis in DSP systems, Monte Carlo simulation. Probabilistic power analysis: Random logic signals, probability & frequency, probabilistic power analysis techniques, signal entropy. Unit – IV 9 Hrs Low Power Design at Circuit level: Power consumption in circuits. Flip Flops & Latches design high							
capacitance nodes, Low Power Desig	lov n a outa	v power digital cells libra at Logic level: Gate re- ation logic.	rry. organization, signal gating, logic encod	ing,	state	machine	
encounig, pre comp	Jui	Un	nit – V			10 Hrs	
Low power Design at Architecture/System Level and Clock distribution: Low power Architecture & Systems: Architectural level estimation & synthesis, Power & performance management, switching activity reduction, parallel architecture with voltage reduction, flow graph transformation, low power arithmetic components, low power memory design. Low power Clock Distribution: Power dissipation in clock distribution, single driver Vs distributed buffers, Zero skew Vs tolerable skew, chip & package co design of clock network. Course Outcomes:							
After going through	n th	is course the student will	be able to:				
 CO1: Acquire the knowledge of the device physics, principles of analysis tools, circuits levels, logic levels and clock distribution techniques for low power designs. CO2: Identify, formulate, and solve engineering system design problems using low power VLSI design approaches and engineering tools. CO3: Use the techniques and skills in system designing through modern engineering tools such as logic works SPICE and description languages such as VHDL and Verilog. CO4: Design digital systems, components or processes to meet the desired low power needs within realistic constraints and create a research oriented platform in thrust areas such as Energy recovery, Quantum computation, Adiabatic computation, etc. Reference Books: 							

1.	Jan M. Rabaey and MassoudPedram, "Low Power Design Methodologies" Kluwer Academic Publishers, 5th reprint, ISBN 978-1-46 13-5975-3, 2002.
2.	Gary K. Yeap, "Practical Low Power Digital VLSI Design", Kluwer Academic Publishers, ISBN 978-1-4613-7778-8, 2002.
3.	Kaushik Roy and Sharat Prasad, "Low-Power CMOS VLSI Circuit Design", John Wiley, 2000. ISBN 13 9788126520237
4.	Ajit Pal, "Low-Power VLSI Circuits and Systems," Springer publications, ISBN: ISBN 978-81-322- 1936-1, 2015
5.	A. P. Chandrakasan & R. W. Broderson: "Low power digital CMOS design", KAP, 1996.
6.	Robert Aitken, Alan Gibbons, Kaijian Shi, Michael Keating, David Flynn, Michael Keating, "Low Power Methodology Manual For System-on-Chip Design" Springer, ISBN 978-0-387-71818-7, 2007.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

			Semester II				
		ADVANCED	EMBEDDED	PROCESSORS			
Course Code	:	18MVE2D2	CIE Marks	3	:	100	
Credits : L:T:P	:	4:0:0	SEE Mark	5	:	100	
Hrs	:	48L	SEE Durat	ion	:	3 Hr	S
		·	Unit – I				10 Hrs
Introduction Embedded Processor Selection, PowerPC, ARM Cortex, SoC, Digital Signal Processors ARM Cortex-M Series Technical Overview Cortex-M Processor Family, Product Portfolio, Advantages, Applications, Cortex Microcontroller Software Interface Standard (CMSIS), General Information, Features							
			Unit – II				10 Hrs
Architecture of ARM Cortex-M Processor Programmer's Model, Application Program Status Register (APSR), Memory System, Exceptions & Interrupts, System Control Block, Debug, Reset & Reset Sequence Instruction Set-I Assembly Language Syntax, Suffixes for Assembly Instructions, Unified Assembly Language,							
		1	U nit – III				9 Hrs
Instruction Set-II Cortex-M4/M7 Specific Instructions, Barrel Shifter Memory System Memory Map, Connecting Cortex-M3/M4 with Memory & Peripherals, Endianness, Data Alignment & Unaligned Data Access Support, Bit Band Operations, Memory Access Attributes, Exclusive Access, Memory Barriers, Memory System in a MCU. Unit – IV 9 Hrs Exceptions & Interrupts Overview of Exceptions and Interrupts, Exception Types, Interrupt Management, Vector Table & Vector Table Relocation, Interrupts Inputs & Pending Behaviours, Exceptions Sequence Overview, Details pf NVIC Registers for Interrupt Control, SCB Registers for Exceptions & Interrupts,						9 Hrs & Vector	
	<u>xce</u>		$\frac{\text{Unit} - V}{\text{Unit} - V}$	Exception bequences.			10 Hrs
Low Power and System Control FeaturesLow Power Designs, Low Power Features, Using WFI & WFE Instructions in for Programming, Developing Low Power Applications, The SysTick Timer, Self-Reset, CPU ID Base Register, Configuration Control Register, Auxiliary Control Registers, Co-Processor Access Control Register.OS Support Features Shadowed Stack Pointer, SVC Exception, PendSV Exception, Context Switching in Action, Exclusive Accesses.Expected Course Outcomes:							
After going through th	is c	ourse the student v	vill be able to:				
CO1. Understand the architecture, instruction set, memory organization and addressing modes of the embedded processors.							
CO2. Realize real t architectures b CO3 Perform mark	ime y m	signal processing aking use of softwurvey of available	g applications over a complete and a complete a complet	& primitive OS opera	tions on	differe	ent ARM

	solving the given problem statement.						
CC	CO4. Engage in self-study to formulate, design, implement, analyze and demonstrate						
	an application realized on ARM development boards through assignments.						
Ref	erence Books:						
1.	Joseph Yiu, "The Definitive Guide to the ARM Cortex-M3& M4 Processors", 3 rd Edition, Newnes (Elsevier), 2014, ISBN:978-93-5107-175-4						
2.	Andrew N Sloss, Dominic Symes, Chris Wright, "ARM System Developers Guide", Elsevier, Morgan Kaufman publishers, 2008, ISBN-13:9788181476463						
3.	Steve Furber, "ARM System on Chip Architecture", Pearson Education Limited, 2nd Edition,2000, ISBN-13:9780201675191						
4.	Technical reference manual for ARM processor cores, including Cortex M3, M4, M7 processor families.						
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Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. Total CIE is 20+50+30=100 Marks.

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

			Semester II				
VLSI DIGITAL SIGNAL PROCESSING SYSTEMS (Group D : Core Elective) (Common to VI SI & ES and CS)							
Course Code	:	18MVE2D3		CIE Marks	:	100	
Credits : L:T:P	:	4:0:0		SEE Marks	:	100	
Hrs	:	48L		SEE Duration	:	3 Hr	s
		Uı	nit — I				10Hrs
Introduction to digital Si Introduction, Typical DS Representations of DSP al	igr SP lgc	al Processing system algorithms, DSF prithms.	tems Application den	nands and scaled C	CMOS	S tech	nologies,
		Un	uit – II				10Hrs
Pipelining and parallel p Introduction, Pipelining of power.	o ro f F	cessing TR Digital filters, p	parallel processing,	pipelining and paralle	el pro	ocessin	g for low
		Un	it – III				10Hrs
Algorithmic strength red Introduction, parallel FIR Rank-Order Filters.	lu fil	ction in filters and ters, Discrete Cosi	l transforms ne transform and in	werse DCT, Parallel a	archit	ectures	s for
Dinalized and navallal D	0.01	Un Unive and Adapti	it – IV vo Filtora				9 Hrs
higher order IIR Digital fi processing for IIR filters, Pipelined Adaptive Digita	lte lov 1 F	rs, parallel process v power IIR digital vilters.	ing for IIR filters, of Filter Design usin	combined pipelining and para	ind p llel p	arallel rocessi	ng,
		Un	uit – V				9 Hrs
Programmable digital Si Introduction, evolution of DSP Processors for Mobil	gn p e a	al Processor rogrammable Digi and wirelesses com	tal Signal processo munication, Proces	ors, Important feature ssor for multimedia si	of I gnal	OSP pr Proces	ocessors, sing.
Expected Course Outcor	ne	S:					
 After going through this course the student will be able to: CO1: Develop a strong grounding in the fundamentals of VLSI digital signal processing , CO2: Understand DSP architectures and CMOS technologies to describe, analyze, and solve problems in VLSI digital signal processing. 							
 CO3: Evaluate and test the modern VLSI digital signal processing systems using simulation tool. CO4: Design suitable algorithm for specific applications & Develop applications using general purpose digital signal processors 							
Reference Dooks:				D · · · ·			••
I Keshab K. Parthi , " 1999.ISBN: 81-265-	v L 10	.SI Digital Signal p 98-6.	processing systems	:Design and impleme	ntatio	on'' W	ıley
2 Rulph chasseing, "D 2005.	igi	tal Signal Processi	ng and applications	s " with C6713 and Co	6416	DSK,	Wiley
3. Nasser Kehtarnavaz, programming,Acade	,, mi	digital Signal Proc c press 2008.	essing System Desi	ign: Lab view based h	ybric	1	

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks.**

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II						
BUSINESS ANALYTICS						
		(Gr	oup G: Global Elective)			
Course Code	:	18CS2G01	CII	E Marks	••	100
Credits L: T: P	:	3:0:0	SE	E Marks	••	100
Hours	:	36L	SEI	E Duration	:	3 hrs

Course Learning Objectives:

Graduates shall be able to

- 1. Formulate and solve business problems to support managerial decision making.
- 2. Explore the concepts, processes needed to develop, report, and analyze business data.
- 3. Use data mining techniques concepts to identify specific patterns in the data
- 4. Interpret data appropriately and solve problems from various sectors such as manufacturing, service, retail, software, banking and finance.

Unit – I	
Business analytics: Overview of Business analytics, Scope of Business analytics, Business 0')7 Hrs
Analytics Process, Relationship of Business Analytics Process and organization,	
competitive advantages of Business Analytics.	
Statistical Tools: Statistical Notation, Descriptive Statistical methods, Review of probability	
distribution and data modelling.	
Unit – II	
Trendiness and Regression Analysis: Modelling Relationships and Trends in Data, simple 0')7 Hrs
Linear Regression. Important Resources, Business Analytics Personnel, Data and models	
for	
Business analytics, problem solving, Visualizing and Exploring Data, Business Analytics	
Technology.	
Unit – III	
Organization Structures of Business analytics, Team management, Management Issues, 0')7 Hrs
Designing Information Policy, Outsourcing, Ensuring Data Quality, Measuring	
contribution of Business analytics, Managing Changes. Descriptive Analytics, Predictive	
Analytics, Predicative Modelling, Predictive analytics analysis.	
Unit – IV	
Forecasting Techniques: Qualitative and Judgmental Forecasting, Statistical Forecasting 0)8 Hrs
Models, Forecasting Models for Stationary Time Series, Forecasting Models for Time	
Series with a Linear Trend, Forecasting Time Series with Seasonality, Regression	
Forecasting with Casual Variables, Selecting Appropriate Forecasting Models.	
Unit –V	
Decision Analysis: Formulating Decision Problems, Decision Strategies with and without 0)7 Hrs
Outcome, Probabilities, Decision Trees, The Value of Information, Utility and Decision	
Making.	

Course	Course Outcomes: After going through this course the student will be able to:					
CO1	Explore the concepts, data and models for Business Analytics.					
CO2	Analyze various techniques for modelling and prediction.					
CO3	Design the clear and actionable insights by translating data.					
CO4	Formulate decision problems to solve business applications					

Refe	rence Books:
1	Marc J. Schniederjans, Dara G. Schniederjans, Christopher M. Starkey, Business analytics Principles, Concepts, and Applications FT Press Analytics, 1 st Edition, 2014, ISBN-13: 978-0133989403, ISBN-10: 0133989402
2	Evan Stubs , The Value of Business Analytics: Identifying the Path to Profitability, John Wiley & Sons, ISBN:9781118983881 DOI:10.1002/9781118983881,1st edition 2014
3	James Evans, Business Analytics, Pearsons Education 2 nd edition, ISBN-13: 978-0321997821 ISBN-10: 0321997824
4	Gary Cokins and Lawrence Maisel, Predictive Business Analytics Forward Looking Capabilities to Improve Business, Wiley; 1 st edition, 2013.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks.**

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II					
INDUSTRIAL AND OCCUPATIONAL HEALTH AND SAFETY (Group G : Global Flective)					
Cour	Course Code: 18CV 2G 02 CIE Marks:100				
Cred	Credits : L: T: P : 3:0:0 SEE Marks :10				
Hour	rs: 36L	SEE Durat	ion:3Hrs		
Cour	se Learning Objectives	:			
1	To understand the Indus	strial and Occupational health and safety and its importance.			
2	To understand the differ	rent materials, occupations to which the employee can exposed to.			
3	To know the characteris	stics of materials and effect on health.			
4	To evaluate the differen	t processes and maintenance required in the industries to avoid accid	lents.		
		UNIT – I	7Hrs		
Industrial safety : Accident, causes, types, results and control, mechanical and electrical hazards, types, causes and preventive steps/procedure, describe salient points of factories act 1948 for health and safety, wash rooms, drinking water layouts, light, cleanliness, fire, guarding, pressure vessels, etc, Safety color codes. Fire prevention and fire fighting, equipment and methods					
		UNIT – II	7Hrs		
Occupational health and safety : Introduction, Health, Occupational health: definition, Interaction between work and health, Health hazards, workplace, economy and sustainable development, Work as a factor in health promotion. Health protection and promotion Activities in the workplace: National governments, Management, Workers, Workers' representatives and unions, Communities, Occupational health professionals. Potential health hazards: Air contaminants, Chemical hazards, Biological hazards, Physical hazards, Ergonomic hazards, Psychosocial factors, Evaluation of health hazards: Exposure measurement techniques, Interpretation of findings recommended exposure limits. Controlling hazards: Engineering controls, Work practice controls, Administrative controls. Occupational diseases: Definition, Characteristics of occupational diseases.					
	UNIT – III 8Hrs				
Hazardous Materials characteristics and effects on health : Introduction, Chemical Agents, Organic Liquids, Gases, Metals and Metallic Compounds, Particulates and Fibers, Alkalies and Oxidizers, General Manufacturing Materials, Chemical Substitutes, Allergens, Carcinogens, Mutagens, Reproductive Hazards, Sensitizers and Teratogens, Recommended Chemical Exposure Limits. Physical Agents, Noise and Vibration, Temperature and Pressure, Carcinogenicity, Mutagenicity and Teratogenicity. Ergonomic Stresses: Stress-Related Health Incidents, Eyestrain, Repetitive Motion, Lower Back Pain, Video Display Terminals					
	UNIT – IV 7Hrs				
Wear and Corrosion and their prevention: Wear- types, causes, effects, wear reduction methods, lubricants-types and applications, Lubrication methods, general sketch, working and applications, i. Screw down grease cup, ii. Pressure grease gun, iii. Splash lubrication, iv. Gravity lubrication, v. Wick feed lubrication vi. Side feed lubrication, vii. Ring lubrication, Definition, principle and factors affecting the corrosion. Types of corrosion, corrosion prevention methods.					
		UNIT – V	7Hrs		
 Periodic and preventive maintenance: Periodic inspection-concept and need, degreasing, cleaning and repairing schemes, overhauling of mechanical components, over hauling of electrical motor, common troubles and remedies of electric motor, repair complexities and its use, definition, need, steps and advantages of preventive maintenance. Steps/procedure for periodic and preventive maintenance of: I. Machine tools, ii. Pumps, iii. Air compressors, iv. Diesel generating (DG) sets, Program and schedule of preventive maintenance of mechanical and electrical equipment, advantages of preventive maintenance. Repair cycle concept and importance. 					

Expe	Expected Course Outcomes:			
After	After successful completion of this course the student will be able to:			
CO1	Explain the Industrial and Occupational health and safety and its importance.			
CO2	Demonstrate the exposure of different materials, occupational environment to which the employee			
	can expose in the industries.			
CO3	Characterize the different type materials, with respect to safety and health hazards of it.			
CO4	Analyze the different processes with regards to safety and health and the maintenance required in			
	the industries to avoid accidents.			
Refei	Reference Books:			
1.	Maintenance Engineering Handbook, Higgins & Morrow, SBN 10: 0070432015 / ISBN			
	13: 9780070432017, Published by McGraw-Hill Education. Da Information Services.			
2.	H. P. Garg, Maintenance Engineering Principles, Practices & Management, 2009, S. Chand and			
	Company, New Delhi, ISBN:9788121926447			
3. Fundamental Principles of Occupational Health and Safety, Benjamin O. ALLI, Second edition				
	International Labour Office – Geneva: ILO, ISBN 978-92-2-120454-1			
4.	Foundation Engineering Handbook, 2008, Winterkorn, Hans, Chapman & Hall London.			
	ISBN:8788111925428.			

Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks.A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks.**

Semester End Evaluation (SEE): Total marks: 100

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II						
MODELING USING LINEAR PROGRAMMING						
	(Group G: Global Elective)					
Course Code	:	18IM2G03		CIE Marks	:	100
Credits L: T: P	:	3:0:0		SEE Marks	:	100
Hours	:	36L		SEE Duration	:	3 hrs

Unit – I		
Linear Programming: Introduction to Linear Programming problem	07 Hrs	
Simplex methods: Variants of Simplex Algorithm – Use of Artificial Variables		
Unit – II		
Advanced Linear Programming : Two Phase simplex techniques, Revised simplex method	07 Hrs	
Duality: Primal-Dual relationships, Economic interpretation of duality		
Unit – III		
Sensitivity Analysis: Graphical sensitivity analysis, Algebraic sensitivity analysis - changes	07 Hrs	
in RHS, Changes in objectives, Post optimal analysis - changes affecting feasibility and		
optimality		
Unit – IV		
Transportation Problem: Formulation of Transportation Model, Basic Feasible Solution		
using North-West corner, Least Cost, Vogel's Approximation Method, Optimality Methods,		
Unbalanced Transportation Problem, Degeneracy in Transportation Problems, Variants in		
Transportation Problems.		
Unit –V		
Assignment Problem: Formulation of the Assignment problem, solution method of	07 Hrs	
assignment problem-Hungarian Method, Variants in assignment problem, Travelling	l	
Salesman Problem (TSP).		

Course Outcomes: After going through this course the student will be able to:		
CO1	Explain the various Linear Programming models and their areas of application.	
CO2	Formulate and solve problems using Linear Programming methods.	
CO3	Develop models for real life problems using Linear Programming techniques.	
CO4	Analyze solutions obtained through Linear Programming techniques.	

1	Taha H A. Operation Research An Introduction, PHI, 8 th Edition, 2009, ISBN: 0130488089.
_	
2	Philips Ravindran and Solberg - Principles of Operations Research – Theory and Practice John
4	Timps, Ravindran and Solderg Timeples of Operations Research Theory and Tractice, Joint
	Wiley & Sons (Asia) Pyt I td 2 nd Edition 2000 ISBN 13: 978-81-265-1256-0
	Whey & Sons (Asia) I W Eta, 2 Edition, 2000, ISBN 15. 776-01-205-1250-0
	Hiller Liberman Nag Basy Introduction to Operation Research Tata McGraw Hill 9th Edition
	Timer, Elociman, Nag, Dasu, infoduction to operation Research, Tata Meoraw Tim y Edition,
2	2012 ISBN 13: 078 0 07 133346 7
3	2012, ISBN 15. 976-0-07-155540-7
Δ	LK Sharma Operations Research Theory and Application Reason Education But Ltd 4th Edition
4	J K Sharma, Operations Research Theory and Application, realson Education PVI Ltd, 4 Edution,
	2000 ISDN 12:078 0 22 062885 2
	2009, ISBN 15. 978-0-25-003885-5.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks.**

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II						
PROJECT MANAGEMENT						
(Group G: Global Elective)						
Course Code	:	18IM2G04		CIE Marks	:	100
Credits L: T: P	:	3:0:0		SEE Marks	:	100
Hours	:	36L		SEE Duration	:	3 hrs

Unit – I		
Introduction : Project Planning, Need of Project Planning, Project Life Cycle, Roles,	07 Hrs	
Responsibility and Team Work, Project Planning Process, Work Breakdown Structure		
(WBS), Introduction to Agile Methodology.		
Unit – II		
Capital Budgeting: Capital Investments: Importance and Difficulties, phases of capital	07 Hrs	
budgeting, levels of decision making, facets of project analysis, feasibility study - a		
schematic diagram, objectives of capital budgeting		
Unit – III		
Project Costing: Cost of Project, Means of Finance, Cost of Production, Working Capital	08 Hrs	
Requirement and its Financing, Profitability Projections, Projected Cash Flow Statement,		
Projected Balance Sheet, Multi-year Projections, Financial Modeling, Social Cost Benefit		
Analysis		
Unit – IV		
Tools & Techniques of Project Management: Bar (GANTT) chart, bar chart for combined	07Hrs	
activities, logic diagrams and networks, Project evaluation and review Techniques (PERT)		
Critical Path Method (CPM), Computerized project management		
Unit-V		
Project Management and Certification: An introduction to SEI, CMMI and project management institute USA – importance of the same for the industry and practitioners.	07 Hrs	
PMBOK 6 - Introduction to Agile Methodology, Themes / Epics / Stories, Implementing		
Agile.		
Domain Specific Case Studies on Project Management: Case studies covering project		
planning, scheduling, use of tools & techniques, performance measurement.		

Course Outcomes: After going through this course the student will be able to:			
CO1	Explain project planning activities that accurately forecast project costs, timelines, and quality.		
CO2	Evaluate the budget and cost analysis of project feasibility.		
CO3	Analyze the concepts, tools and techniques for managing projects.		
CO4	Illustrate project management practices to meet the needs of Domain specific stakeholders from multiple sectors of the economy (i.e. consulting, government, arts, media, and charity organizations).		

Reference Books:

1	Prasanna Chandra, Project Planning Analysis Selection Financing Implementation & Review, Tata McGraw Hill Publication, 8 th Edition, 2010, ISBN 0-07-007793-2.
2	Project Management Institute, A Guide to the Project Management Body of Knowledge (PMBOK Guide), 5 th Edition, 2013, ISBN: 978-1-935589-67-9
3	Harold Kerzner, Project Management A System approach to Planning Scheduling & Controlling, John Wiley & Sons Inc., 11 th Edition, 2013, ISBN 978-1-118-02227-6.
4	Rory Burke, Project Management – Planning and Controlling Techniques, John Wiley & Sons, 4 th Edition, 2004, ISBN: 9812-53-121-1

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks**.

Scheme of Semester End Examination (SEE) for 100 marks:

II Semester				
ENERGY MANAGEMENT				
(Group G: Global Elective)				
Course Code: 18CH2G05	CIE Marks: 100			
Credits: L:T:P: 3:0:0 SEE Marks: 100				
Hours: 36L	SEE Hrs: 3			

Course Learning Objectives(CLO):

Students are able to:

- 1. Explain the importance of energy conservation and energy audit.
- 2. Understand basic principles of renewable sources of energy and technologies.
- 3. Outline utilization of renewable energy sources for both domestics and industrial application.
- 4. Analyse the environmental aspects of renewable energy resources.

08 Hrs Unit-I **Energy conservation:** Principles of energy conservation, Energy audit and types of energy audit, Energy conservation approaches, Cogeneration and types of cogeneration, Heat Exchangers and classification. Unit-II **07 Hrs** Wet Biomass Gasifiers: Introduction, Classification of feedstock for biogas generation, Biomass conversion technologies: Wet and dry processes, Photosynthesis, Biogas generation, Factors affecting bio-digestion, Classification of biogas plants, Floating drum plant and fixed dome plant their advantages and disadvantages. Unit -III 07 Hrs **Dry Biomass Gasifiers :** Biomass energy conversion routes, Thermal gasification of biomass, Classification of gasifiers, Fixed bed systems: Construction and operation of up draught and down draught gasifiers. Unit -IV 07 Hrs **Solar Photovoltaic:**

Principle of photovoltaic conversion of solar energy, Types of solar cells and fabrication. **Wind Energy:**

Unit -V

Classification, Factors influencing wind, WECS & classification.

Alternative liquid fuels:

Introduction, Ethanol production: Raw materials, Pre-treatment, Conversion processes with detailed flow sheet. Gasification of wood: Detailed process, Gas purification and shift conversion, Biofuel from water hyacinth.

Course outcomes (CO):

07 Hrs

On completion of the course, the student should have acquired the ability to CO1: Understand the use alternate fuels for energy conversion CO2: Develop a scheme for energy audit CO3: Evaluate the factors affecting biomass energy conversion CO4: Design a biogas plant for wet and dry feed **Reference Books:** Nonconventional energy, Ashok V Desai, 5th Edition, 2011, New Age International (P) 1 Limited, ISBN 13: 9788122402070. 2 Biogas Technology - A Practical Hand Book, Khandelwal K C and Mahdi S S, Vol. I & II, 1986, McGraw-Hill Education, ISBN-13: 978-0074517239. Biomass Conversion and Technology, Charles Y Wereko-Brobby and Essel B Hagan, 1st 3 Edition, 1996, John Wiley & Sons, ISBN-13: 978-0471962465. Solar Photovoltaics: Fundamental Applications and Technologies, C. S. Solanki, 2nd 4 Edition, 2009, Prentice Hall of India, ISBN:9788120343863.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks):

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) Solving innovative problems 2) Seminar/new developments in the related course 3) Laboratory/ field work 4) mini project.

Total CIE is 20+50+30 = 100 marks.

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II						
INDUSTRY 4.0						
	(Group G: Global Elective)					
Course Code	:	18ME2G06		CIE Marks	:	100
Credits L: T: P	:	3:0:0		SEE Marks	:	100
Hours	:	36L		SEE Duration	:	3 hrs

Unit – I		
Introduction: Industrial, Internet, Case studies, Cloud and Fog, M2M Learning and	07 Hrs	
Artificial Intelligence, AR, Industrial Internet Architecture Framework (IIAF), Data		
Management.		
Unit – II		
The Concept of the IIoT: Modern Communication Protocols, Wireless Communication	07 Hrs	
Technologies, Proximity Network Communication Protocols, TCP/IP, API: A Technical		
Perspective, Middleware Architecture.		
Unit – III		
Data Analytics in Manufacturing: Introduction, Power Consumption in manufacturing,	08 Hrs	
Anomaly Detection in Air Conditioning, Smart Remote Machinery Maintenance Systems		
with Komatsu, Quality Prediction in Steel Manufacturing.		
Internet of Things and New Value Proposition, Introduction, Internet of Things Examples,		
IoTs Value Creation Barriers: Standards, Security and Privacy Concerns.		
Advances in Robotics in the Era of Industry 4.0, Introduction, Recent Technological		
Components of Robots, Advanced Sensor Technologies, Artificial Intelligence, Internet of		
Robotic Things, Cloud Robotics.		
Unit – IV		
Additive Manufacturing Technologies and Applications: Introduction, Additive	07 Hrs	
Manufacturing (AM) Technologies, Stereo lithography, 3DP, Fused Deposition Modeling,		
Selective Laser Sintering, Laminated Object Manufacturing, Laser Engineered Net		
Shaping, Advantages of Additive Manufacturing, Disadvantages of Additive		
Manufacturing.		
Advances in Virtual Factory Research and Applications, The State of Art, The Virtual		
Factory Software, Limitations of the Commercial Software		
Unit –V		
Augmented Reality: The Role of Augmented Reality in the Age of Industry 4.0,	07 Hrs	
Introduction, AR Hardware and Software Technology, Industrial Applications of AR,		
Maintenance, Assembly, Collaborative Operations, Training.		
Smart Factories: Introduction, Smart factories in action, Importance, Real world smart		
factories, The way forward.		
A Roadmap: Digital Transformation, Transforming Operational Processes, Business		
Models, Increase Operational Efficiency, Develop New Business Models.		

Cours	Course Outcomes: After going through this course the student will be able to:					
CO1	Understand the opportunities, challenges brought about by Industry 4.0 for benefits of					
	organizations and individuals					
CO2	Analyze the effectiveness of Smart Factories, Smart cities, Smart products and Smart services					
CO3	Apply the Industrial 4.0 concepts in a manufacturing plant to improve productivity and profits					
CO4	Evaluate the effectiveness of Cloud Computing in a networked economy					

R	eference Books:
1	Alasdair Gilchrist, INDUSTRY 4.0 THE INDUSTRIAL INTERNET OF THINGS, Apress
	Publisher, ISBN-13 (pbk): 978-1-4842-2046-7
2	Alp Ustundag, Emre Cevikcan, Industry 4.0: Managing The Digital Transformation, Springer, 2018
	ISBN 978-3-319-57869-9.
	Ovidiu Vermesan and Peer Friess, Designing the industry - Internet of things connecting the
3	physical, digital and virtual worlds, Rivers Publishers, 2016 ISBN 978-87-93379-81-7
4	Christoph Jan Bartodziej, The concept Industry 4.0- An Empirical Analysis of Technologies and
	Applications in Production Logistics, Springer Gabler, 2017 ISBN 978-3-6581-6502-4.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks**.

Scheme of Semester End Examination (SEE) for 100 marks:

Semester: II						
ADVANCED MATERIALS						
	-	<u> </u>	Froup G: Global Electiv	/e)	1	
Course Code	:	18ME2G07		CIE Marks	:	100
Credits L: T: P	:	3:0:0		SEE Marks	:	100
Hours	:	36L		SEE Duration	:	3 hrs

Unit – I				
Classification and Selection of Materials: Classification of materials. Properties required	07 Hrs			
in Engineering materials, Criteria of selection of materials. Requirements / needs of				
advance materials.				
Unit – II				
Non Metallic Materials: Classification of n on metallic materials, Rubber : Properties,	07 Hrs			
processing and applications. Plastics : Thermosetting and Thermoplastics, Applications and				
properties. Ceramics : Properties and applications. Adhesives: Properties and applications.				
Optical fibers : Properties and applications. Composites : Properties and applications.				
Unit – III				
High Strength Materials: Methods of strengthening of alloys, Materials available for	08 Hrs			
high strength applications, Properties required for high strength materials, Applications of				
high strength materials				
Unit – IV				
Low & High Temperature Materials	07 Hrs			
Properties required for low temperature applications, Materials available for low				
temperature applications, Requirements of materials for high temperature applications,				
Materials available for high temperature applications, Applications of low and high				
temperature materials.				
Unit –V				
Nanomaterials: Definition, Types of nanomaterials including carbon nanotubes and	07 Hrs			
nanocomposites, Physical and mechanical properties, Applications of nanomaterials				

Cours	Course Outcomes: After going through this course the student will be able to:				
CO1	Describe metallic and non metallic materials				
CO2	Explain preparation of high strength Materials				
CO3	Integrate knowledge of different types of advanced engineering Materials				
CO4	Analyse problem and find appropriate solution for use of materials.				

R	eference Books:
1	Donald R. Askeland, and Pradeep P. Fulay, The Science & Engineering of Materials, 5th Edition, Thomson, 2006, ISBN 12,078,0524552068
	110111s011, 2000, ISBN-15-978-0554555908
2	Gregory L. Timp, Nanotechnologym 1999th Editionmm Springer, 1999 ISBN-13: 978-0387983349
	Dr. VD Kodgire and Dr. S V Kodgire, Material Science and Metallurgym 42nd Edition 2018,
3	Everest Publishing House ISBN NO: 81 86314 00 8
4	N Bhatnagar, T S Srivatsan, Processing and Fabrication of Advanced Materials, 2008, IK
	International, ISBN: 978819077702

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project. **Total CIE is 20+50+30=100 Marks**.

Scheme of Semester End Examination (SEE) for 100 marks:

	Semester: II					
	COMPOSITE MATERIALS SCIENCE AND ENGINEERING (Common to AS, BT, CH, CV, IM, ME)					
Course Code: 18CHY2G08CIE Marks: 100						
Cree	lits: L:T:P:S: 3:1:0:0		SEE Marks: 100			
Hou	rs: 36L +12T		SEE Duration: 3Hrs			
Cou	rse Learning Objectives:					
1	Understand the properties of	composite materials.				
2	Apply the basic concepts of	Chemistry to develop futuristic	composite materials for hig	h-tech		
	applications in the area of En	gineering.				
3	Impart knowledge in the diff	erent fields of material chemistry	y so as to apply it to the pro	oblems		
	in engineering field.					
4	Develop analytical capabilit	ies of students so that they can	n characterize, transform a	nd use		
	materials in engineering and	apply knowledge gained in solvir	ng related engineering probl	ems.		
		Unit-I		1		
Intr	oduction to composite materi	als		07		
Func	lamentals of composites –	need for composites – Enhai	ncement of properties –	Hrs		
Clas	sification based on matrix- Pol	lymer matrix composites (PMC)	, Metal matrix composites			
(MN	IC), Ceramic matrix composi	tes (CMC) – Constituents of c	composites, Interfaces and			
Inter	phases, Distribution of cons	stituents, Types of Reinforcem	nents, Particle reinforced			
com	posites, Fibre reinforced comp	posites. Fiber production techniq	jues for glass, carbon and			
cera	me fibers Applications of varie	Jus types of composites.				
Doly	mon motnin compositos (DM	$\frac{1}{1}$		00		
Poly	mer matrix composites (Pivio	C) ing Thermonlectic reging & Flee	stomore	Uð Ung		
Poin	forcement fibres Types Poy	ing Woven febrics PMC n	wrocossos Hand Lavun	nis		
Reinforcement fibres-Types, Rovings, woven fabrics. PMC processes – Hand Layup						
Transfer Moulding – Pultrusion – Filament winding – Injection moulding Glass fibre and						
carb	on fibre reinforced composit	es (GFRP & CFRP). Laminat	tes- Balanced Laminates.			
Symmetric Laminates Angle Ply Laminates Cross Ply Laminates Mechanical Testing of						
PMC	C- Tensile Strength, Flexural S	Strength, ILSS, Impact Strength-	- As per ASTM Standard.			
Applications of PMC in aerospace, automotive industries.						
	<u></u>	Unit -III				
Cera	amic matrix composites and s	pecial composites		07		
Engi	neering ceramic materials – pr	operties – advantages – limitation	ns – monolithic ceramics –	Hrs		
need	for CMC – ceramic matrix – v	various types of ceramic matrix c	omposites- oxide ceramics			
-no	n oxide ceramics – Aluminium	oxide – silicon nitride – reinford	cements – particles- fibres-			
whis	kers. Sintering – Hot pressing	 Cold Isostatic Pressing (CIPin 	g) – Hot isostatic pressing			
(HIP	ing). Applications of CMC	in aerospace, automotive ind	dustries- Carbon /carbon			
com	posites $-$ advantages of carbo	on matrix $-$ limitations of carb	on matrix carbon fibre –			
chen	chemical vapour deposition of carbon on carbon fibre perform. Sol-gel technique- Processing					
of Ceramic Matrix composites.						
Unit –IV						
Char	Metal matrix composites 07					
odya	unaracteristics of MINU, various types of metal matrix composites alloy vs. MMC, Hrs					
reinf	reinforcement – volume fraction – rule of mixtures Processing of MMC – powder metallurgy					
proc	process – diffusion bonding – stir casting – squeeze casting, a sprav process. Liquid					
infilt	infiltration In-situ reactions-Interface-measurement of interface properties- applications of					
MM	MMC in aerospace, automotive industries.					
	······································	Unit –V		1		
Polv	mer nano composites			07		
Intro	duction and Significance of	polymer Nano composites. Int	ercalated And Exfoliated	Hrs		
Nano	Nanocomposites. Classification of Nano fillers- nanolayers, nanotubes, nanoparticles.					

Preparation of Polymer Nano composites by Solution, In-situ Polymerization and melt mixing techniques. Characterization Of polymer nanocomposites- XRD, TEM, SEM and AFM. Mechanical and Rheological properties of Polymer Nano composites. Gas barrier, Chemical-Resistance, Thermal and Flame retardant properties of polymer nanocomposites. Optical properties and Biodegradability studies of Polymer nanocomposites, Applications of polymer nano-composites.

Course	Course Outcomes: After completing the course, the students will be able to						
CO1:	Understand the purpose and the ways to develop new materials upon proper						
	combination of known materials.						
CO2:	Identify the basic constituents of a composite materials and list the choice of materials						
	available						
CO3:	Will be capable of comparing/evaluating the relative merits of using alternatives for						
	important engineering and other applications.						
CO4:	Get insight to the possibility of replacing the existing macro materials with nano-						
	materials.						

Reference Books

1	Composite Materials Science and Engineering, Krishan K Chawla, 3rd Edition
	Springer-verlag Gmbh, , ISBN: 9780387743646, 0387743642
2	The Science and Engineering of Materials, K Balani, Donald R Askeland,6 th Edition-
2	Cengage, Publishers, ISBN: 9788131516416
•	Polymer Science and Technology, Joel R Fried, 2 nd Edition, Prentice Hall, ISBN:
3	9780137039555
4	Nanomaterials and nanocomposites, Rajendra Kumar Goyal, 2 nd Edition, CRC
4	Press-Taylor & Francis, ISBN: 9781498761666, 1498761666

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks)

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) solving innovative problems 2) seminar/new developments in the related course 3) Laboratory/field work 4) mini project.

Total CIE is 20+50+30=100 Marks.

Scheme of Semester End Examination (SEE) for 100 marks:

Semester : II					
PHYSICS OF MATERIALS					
(Group G: Global Elective)					
Course Code: 18PHY2G09		CIE Marks: 100			
Credits: L:T:P:: 3:0:0		SEE Marks: 100			
Hours: 36		SEE Duration: 3Hrs			

Course Learning Objectives (CLO):

Student are able to

1. Classify the crystals based on lattice parameters.

2.Explain the behavior of Dielectrics with change in frequency.

3.Classify the magnetic materials based on Quantum theory as well understand superconductors.

4.Explain direct and indirect bandgap semiconductors, polymer semiconductors and Photoconductive polymers.

5.Describe the behavior of Smart materials and its phases and apply to Engineering applications.

Unit-I	07 Hrs	
Crystal Structure :		
Symmetry elements-seven crystals systems-Reciprocal lattice-Packing fraction,	Lattice	
Vibration-Brillouin zones, Analysis of Crystal structure using XRD, Thermal property	ies.	
Unit-II	07 Hrs	
Dielectric Materials:		
Basic concepts-Langevin's Theory of Polarisation-Clausius-Mossotti Relation	on-Ferro	
electricity-Piezoelectricity-Properties of Dielectric in alternating fields-The	complex	
Dielectric Constant and Dielectric Loss, Polarizability as a function of frequency-	Complex	
dielectric constant of non-polar solids-Dipolar relaxation, Applications.		
Unit -III	07Hrs	
Magnetic Materials :		
Dia and Paramagnetic materials-Quantum theory of paramagnetic materials-Paramagnetic		
susceptibility of conduction electrons-Ferro-anti ferromagnetic materials-Superco	nductors	
and Applications		
Unit -IV	07 Hrs	
Semiconducting Materials		
Semiconductor-Direct and Indirect bonding characteristics-Importance of (Quantum	
confinement-quantum wires and dots-Ferro electric semiconductors-applications-	Polymer	
semiconductors-Photo conductive polymers, Applications.		
Unit -V	08 Hrs	
Novel Materials		
Smart materials-shape memory alloys-shape memory effects-Martensitia Transfe	ormation	
functional properties-processing-texture and its nature.		

Reference Books:				
1.	Solid State Physics, S O Pillai, 6 th Edition, New Age International Publishers, ISBN 10-			
	8122436978.			
2.	Introduction to Solid State Physics, C.Kittel, 7 th Edition, 2003, John Wiley & Sons, ISBN			
	9971-51-180.			
3.	Material Science, Rajendran V and Marikani, 1st Edition, Tata McGraw Hill, ISBN 10-			
	0071328971.			
4.	The Science and Engineering of Materials, Askeland, Fulay, Wright, Balanai, 6 th Edition,			
	Cengage Learning, ISBN-13:978-0-495-66802-2.			

Course Outcomes (CO's):
CO1: Analyse crystals using XRD technique.
CO2: Explain Dielectric and magnetic materials.
CO3:Integrate knowledge of various types of advanced engineering Materials.
CO4: Use materials for novel applications.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks):

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) Solving innovative problems 2) Seminar/new developments in the related course 3) Laboratory/ field work 4) mini project.

Total CIE is 20+50+30 = 100 marks.

Scheme of Semester End Examination (SEE) for 100 marks:

	II Semester			
ADVANCED STATISTICAL METHODS				
(Global Elective)				
Course Code: 18MAT2G10		CIE Marks: 100		
Credits: L:T:P:: 3:0:0		SEE Marks: 100		
Hours: 36		SEE Duration: 3Hrs		

Course Learning Objectives (CLO):

Students are able to:

1. Adequate exposure to learn sampling techniques, random phenomena for analyzing data for solving real world problems.

2. To learn fundamentals of estimation and problems used in various fields of engineering and science.

3. Explore the fundamental principles of statistical inference and tests of hypothesis.

4. Apply the concepts of regression and statistical models to solve the problems of engineering applications.

Unit-I	07 Hrs	
Sampling Techniques:		
Random numbers, Concepts of random sampling from finite and infinite populations	, Simple	
random sampling (with replacement and without replacement). Expectation and	standard	
error of sample mean and proportion.		
Unit-II	07 Hrs	
Estimation:		
Point estimation, Estimator and estimate, Criteria for good estimates - unbiasedness,		
likelihood estimation Properties of maximum likelihood estimator (no proofs). Co	nfidence	
intervals population mean (large sample) population proportion	muence	
Intervals-population mean (large sample), population proportion.	07Um	
	0/115	
Tests of Hypothesis:		
Principles of Statistical Inference, Formulation of the problems with examples, Simple and		
composite hypothesis, Null and alternative hypothesis, Tests - type I and type	II error,	
Testing of mean and variance of normal population (one sample and two sample	les), Chi	
squared test for goodness of fit.		
Unit -IV	07 Hrs	
Linear Statistical Models:		
Definition of linear model and types, One way ANOVA and two way ANOVA models-one		
observation per cell, multiple but equal number of observation per cell.		
Unit -V	08 Hrs	
Linear Regression:		
Simple linear regression, Estimation of parameters, Properties of least square estimators,		
Estimation of error variance, Multivariate data, Multiple linear regressions, Multiple and		
partial correlation, Autocorrelation-introduction and plausibility of serial dep	endence,	

sources of autocorrelation, Durbin-Watson test for auto correlated variables.

Reference Books:			
1	Fundamentals of Statistics (Vol. I and Vol. II), A. M. Goon, M. K. Gupta and B.		
	Dasgupta, 3 rd Edition, 1968, World Press Private Limited, ISBN-13: 978-8187567806.		
2	Applied Statistics and Probability for Engineers, John Wiley & Sons, Inc., 3 rd Edition,		
	2003, ISBN 0-471-20454-4.		
3	S.C. Gupta, V.K. Kapoor, Fundamentals of Mathematical Statistic, D. C. Montgomery		
	and G. C. Runger, 10 th Edition, 2000, A Modern Approach, S Chand Publications,		
	ISBN 81-7014-791-3.		
4	Regression Analysis: Concepts and Applications , F. A. Graybill and H. K. Iyer,		
	Belmont, Calif, 1994, Duxbury Press, ISBN-13: 978-0534198695.		

Course outcomes (CO's):

On completion of the course, the student should have acquired the ability to

CO1: Identify and interpret the fundamental concepts of sampling techniques, estimates and types, hypothesis, linear statistical models and linear regression arising in various fields engineering.

CO2: Apply the knowledge and skills of simple random sampling, estimation, null and alternative hypotheses, errors, one way ANOVA, linear and multiple linear regressions.

CO3: Analyze the physical problem to establish statistical/mathematical model and use appropriate statistical methods to solve and optimize the solution.

CO4: Distinguish the overall mathematical knowledge gained to demonstrate the problems of sampling techniques, estimation, tests of hypothesis, regression and statistical model arising in many practical situations.

Scheme of Continuous Internal Evaluation (CIE); Theory (100 Marks):

CIE is executed by way of quizzes (Q), tests (T) and assignments. A minimum of two quizzes are conducted and each quiz is evaluated for 10 marks adding up to 20 marks. Faculty may adopt innovative methods for conducting quizzes effectively. The three tests are conducted for 50 marks each and the sum of the marks scored from three tests is reduced to 50 marks. A minimum of two assignments are given with a combination of two components among 1) Solving innovative problems 2) Seminar/new developments in the related course 3) Laboratory/ field work 4) mini project.

Total CIE is 20+50+30 = 100 marks.

Scheme of Semester End Examination (SEE) for 100 marks:



Curriculum Design Process

Academic Planning And Implementation



Process For Course Outcome Attainment



Final CO Attainment Process





Program Outcome Attainment Process
PROGRAM OUTCOMES (PO)

- M. Tech. in VLSI Design and Embedded Systems Program graduates will be able to:
- PO1: Independently carry out research /investigation and development work to solve practical problems related to VLSI Design & Embedded Systems
- PO2: Write and present a substantial technical report/document in the field of VLSI Design & Embedded Systems
- PO3: Demonstrate a degree of mastery over the areas of VLSI Design & Embedded Systems. The mastery should be at a level higher than the requirements in the bachelor's in Electronics & Communication Engineering.
- PO4: Conceptualize and solve VLSI design and Embedded system problems and propose optimal solutions.
- PO5: Analyze, learn and apply appropriate techniques, resources and modern engineering/IT tools in core and allied areas.
- PO6: Acquire professional and intellectual integrity and ethics of research and execute projects efficiently.